Technical Reference

Tektronix

Tektronix Logic Analyzer Series Product Specifications

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Specifications and Characteristics

This document lists the specifications for the Tektronix Logic Analyzer family products.

Characteristic Tables

All specifications are guaranteed unless noted *Typical*. Typical characteristics describe typical or average performance and provide useful reference information.

Specifications that are marked with the ✔ symbol are checked directly (or indirectly) in the *Performance Verification* chapter of module's or mainframe service manual.

For mainframes and modules, the performance limits in this specification are valid with these conditions:

- The logic analyzer must be in an environment with temperature, altitude, humidity, and vibration within the operating limits described in these specifications.

- The logic analyzer must have had a warm-up period of at least 30 minutes.

For modules, the performance limits in this specification are valid with these conditions:

- The modules must be installed in a Logic Analyzer Mainframe.

- The module must have been calibrated/adjusted at an ambient temperature between +20 °C and +30 °C.

- The DSO module must have had its signal-path-compensation routine (self calibration or self cal) last executed after at least a 30 minute warm-up period.

- After the warm-up period, the DSO module must have had its signal-path-compensation routine last executed at an ambient temperature within ±5 °C of the current ambient temperature.

For optimum performance using an external oscilloscope, please consult the documentation for any external oscilloscopes used with your Tektronix Logic Analyzer to determine the warm-up period and signal-path compensation requirements.

Atmospheric Characteristics for the Tektronix Logic Analyzer Family

Table 1 lists the Atmospheric characteristics of all components in the Tektronix Logic Analyzer family.

Table 1: Atmospheric characteristics

Characteristic	Description
Temperature: Operating and nonoperating	Operating (no media in floppy disk drive): +5 °C to +50 °C, 15 °C/hr maximum gradient, non-condensing (derated 1 °C per 1000 ft above 5000 foot altitude)[1] Nonoperating (no media in floppy disk drive or CD ROM drive): −20 °C to +60 °C, 15 °C/hr maximum gradient, non-condensing.
Relative Humidity: Operating and nonoperating	Operating (no media in floppy disk drive or CD ROM drive): 20% to 80% relative humidity, non-condensing. Maximum wet bulb temperature: +29 °C (derates relative humidity to approximately 22% at +50 °C).[2, 3] Nonoperating (no media in floppy disk drive or CD ROM drive): 8% to 80% relative humidity, non-condensing. Maximum wet bulb temperature: +29 °C (derates relative humidity to approximately 22% at +50 °C).[4]
Altitude: Operating and nonoperating	Operating: To 10,000 ft (3040 m), (derated 1 °C per 1000 ft (305 m) above 5000 ft (1524 m) altitude) Nonoperating: 40,000 ft (12190 m).

[1] **TLA7Axx series module operating temperature is +40 °C maximum.**

[2] **TLA7Axx series module operating humidity is 5% to 90% up to +30 °C, 75% from +30 to +40 °C, noncondensing. Maximum wet‑bulb temperature is +29.4 °C.**

[3] **TLA7NAx series module operating humidity is 5% to 90% up to +30 °C, 75% from +30 to +40 °C, 45 % from +40 to +50 °C, noncondensing. Maximum wet‑bulb temperature is +29.4 °C.**

[4] **TLA7Axx/TLA7NAx series module nonoperating humidity is 5% to 90% limited by a wet bulb temperature of +40 °C.**

Certifications and Compliances

Table 2 lists the certifications and compliances of the Tektronix Logic Analyzer family. The certifications and compliances apply to all components of the Tektronix Logic Analyzer family unless noted otherwise.

Table 2: Certifications and compliances

Category	Standards or description
EC Declaration of Conformity – EMC	Meets intent of Directive 89/336/EEC for Electromagnetic Compatibility. Compliance was demonstrated to the following specifications as listed in the Official Journal of the European Communities:
	EN 61326 EMC requirements for Class A electrical equipment for measurement, control and laboratory use.[1]
	IEC 61000-4-2 Electrostatic discharge immunity (Performance criterion B) IEC 61000-4-3 RF electromagnetic field immunity (Performance criterion A) IEC 61000-4-4 Electrical fast transient / burst immunity (Performance criterion B) IEC 61000-4-5 Power line surge immunity (Performance criterion B) IEC 61000-4-6 Conducted RF immunity (Performance criterion A) IEC 61000-4-11 Voltage dips and interruptions immunity (Performance criterion B)
	EN 61000-3-2 AC power line harmonic emissions
Australia / New Zealand Declaration of Conformity – EMC	Complies with EMC provision of Radiocommunications Act per the following standard(s):
	AS/NZS 2064.1/2 Industrial, Scientific, and Medical Equipment: 1992
EC Declaration of Conformity – Low Voltage	Compliance was demonstrated to the following specification as listed in the Official Journal of the European Communities:
	Low Voltage Directive 73/23/EEC, amended by 93/68/EEC
	EN 61010-1/A2:1995 Safety requirements for electrical equipment for measurement control and laboratory use.
U.S. Nationally Recognized Testing Laboratory Listing	UL3111-1 Standard for electrical measuring and test equipment.
Canadian Certification	CAN/CSA C22.2 No. 1010.1 Safety requirements for electrical equipment for measurement, control, and laboratory use.
Additional Compliance	IEC61010-1/A2:1995 Safety requirements for electrical equipment for measurement, control, and laboratory use.
Installation (Overvoltage) Category	Terminals on this product may have different installation (overvoltage) category designations. The installation categories are:
	CAT II Local-level mains (wall sockets). Equipment at this level includes appliances, portable tools, and similar products. Equipment is usually cord-connected.

[1] **Emissions which exceed the levels required by this standard may occur when this equipment is connected to a test object.**

Table 2: Certifications and compliances (Cont.)

Category	Standards or description	
Pollution Degree	A measure of the contaminates that could occur in the environment around and within a product. Typically the internal environment inside a product is considered to be the same as the external. Products should be used only in the environment for which they are rated.	
	Pollution Degree 2	Normally only dry, nonconductive pollution occurs. Occasionally a temporary conductivity that is caused by condensation must be expected. This location is a typical office/home environment. Temporary condensation occurs only when the product is out of service.
Safety Certification Compliance		
Equipment Type	Test and measuring	
Safety Class	Class 1 (as defined in IEC61010-1, Annex H) – grounded product	
Overvoltage Category	Overvoltage Category II (as defined in IEC61010-1, Annex J)	
Pollution Degree	Pollution Degree 2 (as defined in IEC61010-1). Note: Rated for indoor use only.	

TLA600 Series Logic Analyzer Specifications

Tables 3 through 17 list the specifications for the TLA600 series logic analyzer.

Table 3: TLA600 input parameters with probes

Characteristic	Description
✓ Threshold Accuracy	±100 mV
Threshold range and step size	Settable from +5 V to −2 V in 50 mV steps
Threshold channel selection	16 threshold groups assigned to channels. P6417 and P6418 probes have two threshold settings, one for the clock/qualifier channel and one for the data channels. P6434 probes have four threshold settings, one for each of the clock/qualifier channels and two for the data channels (one per 16 data channels).
✓ Channel-to-channel skew	≤ 1.6 ns maximum
Channel-to-channel skew (Typical)	≤ 1.0 ns
Sample uncertainty	
Asynchronous:	Sample period
Synchronous:	500 ps
Probe input resistance (Typical)	20 kΩ
Probe input capacitance: P6417, P6434 (Typical)	2 pF
Probe input capacitance: P6418 (Typical)	1.4 pF data channels 2 pF CLK/Qual channels
Minimum slew rate (Typical)	0.2 V/ns
Maximum operating signal	6.5 V_{p-p} −3.5 V absolute input voltage minimum 6.5 V absolute input voltage maximum

Probe overdrive:
    P6417, P6418
 	
    P6434
	
	±250 mV or ±25% of signal swing minimum required beyond threshold, whichever is greater
	±300 mV or ±25% of signal swing minimum required beyond threshold, whichever is greater
	±4 V maximum beyond threshold

Maximum nondestructive input signal to probe	±15 V
Minimum input pulse width signal (single channel) (Typical)	2 ns
Delay time from probe tip to input probe connector (Typical)	7.33 ns

Table 4: TLA600 timing latencies

Characteristic	Description
System Trigger and External Signal Input Latencies[1] (Typical)	
External System Trigger Input to LA Probe Tip[2]	–266 ns
External Signal Input to LA Probe Tip via Signal 3, 4[3]	–212 ns + Clk
External Signal Input to LA Probe Tip via Signal 1, 2[3, 4]	–208 ns + Clk
System Trigger and External Signal Output Latencies (Typical)	
LA Probe Tip to External System Trigger Out[5]	376 ns + SMPL
LA Probe Tip to External Signal Out via Signal 3, 4[5]	
OR function	366 ns + SMPL
AND function	379 ns + SMPL
LA Probe Tip to External Signal Out via Signal 1, 2[4, 5]	
normal function	364 ns + SMPL
inverted logic on backplane	364 ns + SMPL

[1] **All system trigger and external signal input latencies are measured from a falling-edge transition (active true low) with signals measured in the wired-OR configuration.**

[2] **In the Waveform window, triggers are always marked immediately except when delayed to the first sample. In the Listing window, triggers are always marked on the next sample period following their occurrence.**

[3] **"Clk" represents the time to the next master clock at the destination logic analyzer. In the asynchronous (or internal) clock mode, this represents the delta time to the next sample clock beyond the minimum asynchronous rate of 4 ns. In the synchronous (or external) clock mode, this represents the time to the next master clock generated by the setup of the clocking state machine and the supplied system under test clocks and qualification data.**

[4] **Signals 1 and 2 (ECLTRG0, 1) are limited to a "broadcast" mode of operation, where only one source is allowed to drive the signal node at any one time. That single source may be utilized to drive any combination of destinations.**

[5] **SMPL represents the time from the event at the probe tip inputs to the next valid data sample. In the Normal Internal clock mode, this represents the delta time to the next sample clock. In the MagniVu Internal clock mode, this represents 500 ps or less. In the External clock mode, this represents the time to the next master clock generated by the setup of the clocking state machine, the system-under-test supplied clocks, and the qualification data.**

Table 5: TLA600 external signal interface

Characteristic	Description
System Trigger Input	TTL compatible input via rear panel mounted BNC connectors
Input Levels V_{IH} V_{IL}	TTL compatible input ≥ 2.0 V ≤ 0.8 V
Input Mode	Falling edge sensitive, latched (active low)
Minimum Pulse Width	12 ns
Active Period	Accepts system triggers during valid acquisition periods via real-time gating, resets system trigger input latch between valid acquisition periods
Maximum Input Voltage	0 to +5 V peak
External Signal Input	TTL compatible input via rear panel mounted BNC connectors
Input Destination	Signal 1, 2, 3, 4
Input Levels V_{IH} V_{IL}	TTL compatible input ≥ 2.0 V ≤ 0.8 V
Input Mode	Active (true) low, level sensitive
Input Bandwidth[1] Signal 1, 2 Signal 3, 4	50 MHz square wave minimum 10 MHz square wave minimum
Active Period	Accepts signals during valid acquisition periods via real-time gating
Maximum Input Voltage	0 to +5 V peak
System Trigger Output	TTL compatible output via rear panel mounted BNC connectors
Source Mode	Active (true) low, falling edge latched
Active Period	Outputs system trigger state during valid acquisition period, resets system trigger output to false state between valid acquisitions
Output Levels V_{OH} V_{OL}	50 Ω back terminated TTL-compatible output ≥ 4 V into open circuit ≥ 2 V into 50 Ω to ground ≤ 0.7 V sinking 10 mA
Output Protection	Short-circuit protected (to ground)
External Signal Output	TTL compatible outputs via rear panel mounted BNC connectors
Source Selection	Signal 1, 2, 3, 4, or 10 MHz clock
Output Modes Level Sensitive	User definable Active (true) low or active (true) high
Output Levels V_{OH} V_{OL}	50 Ohm back terminated TTL output ≥ 4 V into open circuit ≥ 2 V into 50 Ω to ground ≤ 0.7 V sinking 10 mA

Table 5: TLA600 external signal interface (Cont.)

Characteristic	Description
Output Bandwidth[2] Signal 1, 2 Signal 3, 4	 50 MHz square wave minimum 10 MHz square wave minimum
Active Period	Outputs signals during valid acquisition periods, resets signals to false state between valid acquisitions Outputs 10 MHz clock continuously
Output Protection	Short-circuit protected (to ground)

[1]   **The Input Bandwidth specification only applies to signals to the modules; it does not apply to signals applied to the External Signal Input and sent back to the External Signal Output.**

[2]   **The Output Bandwidth specification only applies to signals from the modules; it does not apply to signals applied to the External Signal Input and sent back to the External Signal Output.**

Table 6: TLA600 channel width and depth

Characteristic	Description	
Number of channels	Product	Channels
	TLA601, TLA611, TLA621	32 data and 2 clock
	TLA602, TLA612, TLA622	64 data and 4 clock
	TLA603, TLA613, TLA623	96 data, 4 clock, and 2 qualifier
	TLA604, TLA614, TLA624	128 data, 4 clock, and 4 qualifier
Acquisition memory depth	Product	Memory depth
	TLA601, TLA602, TLA603, TLA604	64 K or 256 K samples[1]
	TLA611, TLA612, TLA613, TLA614	64 K or 256 K samples[1]
	TLA621, TLA622, TLA623, TLA624	1 M samples

[1]   **PowerFlex options**

Table 7: TLA600 clocking

Characteristic	Description	
Asynchronous clocking		
✓ Internal sampling period[1]	4 ns to 50 ms in a 1–2–5 sequence 2 ns in 2x Clocking mode	
✓ Minimum recognizable word[2] (across all channels)	Channel-to-channel skew + sample uncertainty	
	Example: for a P6417, P6418, or P6434 Probe and a 4 ns sample period = 1.6 ns + 4 ns = 5.6 ns	
Synchronous clocking		
Number of clock channels[3]	Product	Clock channels
	TLA601, TLA611, TLA621	2
	TLA602, TLA612, TLA622	4
	TLA603, TLA613, TLA623	4
	TLA604, TLA614, TLA624	4
Number of qualifier channels[5]	Product	Qualifier channels
	TLA601, TLA611, TLA621	0
	TLA602, TLA612, TLA622	0
	TLA603, TLA613, TLA623	2
	TLA604, TLA614, TLA624	4

✓ Setup and hold window size
(data and qualifiers)
	Maximum window size = Maximum channel-to-channel skew + (2 x sample
	      uncertainty) + 0.4 ns
	Maximum setup time = User interface setup time + 0.8 ns
	Maximum hold time = User interface hold time + 0.2 ns
	
	Examples: for a P6417 or a P6418 probe and user interface
	      setup and hold of 2.0/0.0 typical:
	Maximum window size = 1.6 ns + (2 x 500 ps) + 0.4ns = 3.0 ns
	Maximum setup time = 2.0 ns + 0.8 ns = 2.8 ns
	Maximum hold time = 0.0 ns + 0.2 ns = 0.2ns	

Setup and hold window size (data and qualifiers) (Typical)	Channel-to-channel skew (*typical*) + (2 x sample uncertainty)	
	Example: for P6417 or P6418 Probe = 1 ns + (2 x 500 ps) = 2 ns	
Setup and hold window range	For each channel, the setup and hold window can be moved from +8.5 ns (Ts) to −7.0 ns (Ts) in 0.5 ns steps (setup time). Hold time follows the setup time by the setup and hold window size.	
✓ Maximum synchronous clock rate[4]	200 MHz in full speed mode (5 ns minimum between active clock edges)	
	100 MHz (10 ns minimum between active clock edges)	
Demux clocking		
TLA603, TLA613, TLA623 TLA604, TLA614, TLA624	Channels multiplex as follows: A3(7:0) to D3(7:0) A2(7:0) to D2(7:0) A1(7:0) to D1(7:0) A0(7:0) to D0(7:0)	

Table 7: TLA600 clocking (Cont.)

Characteristic	Description
TLA601, TLA611, TLA621 TLA602, TLA612, TLA622	Channels multiplex as follows: A3(7:0) to C3(7:0) A2(7:0) to C2(7:0) A1(7:0) to D1(7:0) TLA602, TLA612, TLA622 A0(7:0) to D0(7:0) TLA602, TLA612, TLA622
Time between DeMux clock edges[4] (Typical)	5 ns minimum between Demux clock edges in full-speed mode 10 ns minimum between Demux clock edges in half-speed mode
Time between DeMux store clock edges[4] (Typical)	10 ns minimum between Demux master clock edges in full-speed mode 20 ns minimum between Demux master clock edges in half-speed mode
Data Rate[4] (Typical)	400 MHz (200 MHz option required) half channel. (Requires channels to be multiplexed.) These multiplexed channels double the memory depth.
Clocking state machine	
Pipeline delays	Each channel can be programmed with a pipeline delay of 0 through 3 active clock edges.

[1]   **It is possible to use storage control and only store data when it has changed (transitional storage).**

[2]   **Applies to asynchronous clocking only. Setup and hold window specification applies to synchronous clocking only.**

[3]   **Any or all of the clock channels may be enabled. For an enabled clock channel, either the rising, falling, or both edges can be selected as the active clock edges. The clock channels are stored.**

[4]   **Full and half speed modes are controlled by PowerFlex options and upgrade kits.**

[5]   **All qualifier channels are stored. For custom clocking there are an additional 4 qualifier channels on C2 3:0 regardless of channel width.**

Table 8: TLA600 trigger system

Characteristic	Description
Triggering Resources	
Word/Range recognizers	16 word recognizers. The word recognizers can be combined to form full width, double bounded, range recognizers. The following selections are available: 16 word recognizers 0 range recognizers 13 word recognizers 1 range recognizer 10 word recognizers 2 range recognizers 7 word recognizers 3 range recognizers 4 word recognizers 4 range recognizers
Range recognizer channel order	From most-significant probe group to least-significant probe group: C3 C2 C1 C0 E3 E2 E1 E0 A3 A2 D3 D2 A1 A0 D1 D0 Q3 Q2 Q1 Q0 CK3 CK2 CK1 CK0 Missing channels for modules with fewer than 136 channels are omitted.
Glitch detector[1,2]	Each channel group can be enabled to detect a glitch

Table 8: TLA600 trigger system (Cont.)

Characteristic	Description
Minimum detectable glitch pulse width (Typical)	2.0 ns (single channel with P6417, P6418, or a P6434 probe)
Setup and hold violation detector[1,3]	Each channel can be enabled to detect a setup and hold violation. The range is from 8 ns before the clock edge to 8 ns after the clock edge. The range can be selected in 0.5 ns increments.
	The setup and hold violation of each window can be individually programmed.
Transition detector[1]	Each channel group can be enabled or disabled to detect a transition between the current valid data sample and the previous valid data sample.
	This mode can be used to create transitional storage selections where all channels are enabled.
Counter/Timers	2 counter/timers, 51 bits wide, can be clocked up to 250 MHz. Maximum count is 2^{51}. Maximum time is 9.007×10^6 seconds or 104 days.
	Counters and timers can be set, reset, or tested and have zero reset latency.
External Signal In[1]	A backplane input signal
External Trigger In	A backplane input signal that causes the main acquisition and the MagniVu acquisition to trigger if they are not already triggered
Active trigger resources	16 maximum (excluding counter/timers)
	Word recognizers are traded off one-by-one as External Signal In, glitch detection, setup and hold detection, or transition detection resources are added.
Trigger States	16
↙ Trigger State sequence rate	Same rate as valid data samples received, 250 MHz maximum
Trigger Machine Actions	
Main acquisition trigger	Triggers the main acquisition memory
Main trigger position	Trigger position is programmable to any data sample (4 ns boundaries)
MagniVu™ acquisition trigger	Triggering of MagniV memory is controlled by the main acquisition trigger
MagniVu™ trigger position	The MagniV trigger position is programmable within 4 ns boundaries and separate from the main acquisition memory trigger position.
Increment counter	Either of the two counter/timers used as counters can be increased.
Start/Stop timer	Either of the two counter/timers used as timers can be started or stopped.
Reset counter/timer	Either of the two counter/timers can be reset.
	When a counter/timer is used as a timer and is reset, the timer continues from the started or stopped state that it was in prior to the reset.
Signal out	A signal sent to the backplane to be used by other instruments
Trigger out	A trigger out signal sent to the backplane to trigger other instruments

Table 8: TLA600 trigger system (Cont.)

Characteristic	Description
Storage Control	
Global storage	Storage is allowed only when a specific condition is met. This condition can use any of the trigger machine resources except for the counter/timers. Storage commands defined in the current trigger state will override the global storage control. Global storage can be used to start the acquisition with storage initially turned on (default) or turned off.
By event	Storage can be turned on or off; only the current sample can be stored. The event storage control overrides any global storage commands.
Block storage	When enabled, 31 samples are stored before and after the valid sample. Not allowed when glitch storage or setup and hold violation is enabled.
Glitch violation storage	The acquisition memory can be enabled to store glitch violation information with each data sample when asynchronous clocking is used. The probe data storage size is reduced by one half (the other half holds the violation information). The fastest asynchronous clocking rate is reduced to 10 ns.
Setup and hold violation storage	The acquisition memory can be enabled to store setup and hold violation information with each data sample when synchronous clocking is used. The probe data storage size is reduced by one half (the other half holds the violation information). The maximum clock rate is reduced by half.

[1] **Each use of External Signal In, glitch detector, setup and hold violation detector, or transition detector requires a trade-off of one word recognizer resource.**

[2] **Any glitch is subject to pulse width variation of up to the channel-to-channel skew specification + 0.5 ns.**

[3] **Any setup value is subject to variation of up to 1.8 ns; any hold value is subject to variation of up to 1.2 ns.**

Table 9: TLA600 MagniVu™ feature

Characteristic	Description
MagniVu memory depth	2016 samples per channel
MagniVu sampling period	Data is asynchronously sampled and stored every 500 ps in a separate high resolution memory. There are no clocking options.

Table 10: TLA600 Data handling

Characteristic	Description
Nonvolatile memory retention time (Typical)	Battery is integral to the NVRAM. Battery life is > 10 years.

Table 11: TLA600 internal controller

Characteristic	Description	
Operating System	Microsoft Windows	
Microprocessor	Intel Celeron, 566 MHz	
Main Memory	SDRAM	
Style	168 pin DIMM, 2 Sockets	
Speed	100 MHz	
Installed Configurations	Minimum 256 MB loaded in one socket Maximum 512 MB with both sockets loaded	
Real-Time Clock and CMOS Setups, Plug & Play NVRAM Retention Time	Battery life is typically > 3 years when the logic analyzer is not connected to line voltage. When connected to line voltage the life of the battery is extended. Lithium battery, CR3032	
Hard Disk Drive	Standard PC compatible IDE (Integrated Device Electronics) hard disk drive residing on an EIDE interface.	
Size	Minimum 10 GByte Maximum 30 GByte Continually subject to change due to the fast-moving PC component environment. These storage capacities valid at product introduction.	
CD-RW Drive	Standard PC compatible IDE (Integrated Device Electronics) 24x-10x-40x CD-RW drive residing on an EIDE interface. Continually subject to change due to the fast-moving PC component environment.	
Floppy Disk Drive	Standard 3.5 inch 1.44-MB PC compatible high-density, double-sided floppy disk drive.	

Table 12: TLA600 display system

Characteristic	Description
Classification	Standard PC graphics accelerator technology (bitBLT-based); capable of supporting both internal color LCD display and external color SVGA/XGA monitor
Display Memory	DRAM-based frame-buffer memory
Size	2 MB
Display Selection	Both front panel and external displays can be used simultaneously, each with independent resolutions. Supports Windows dual-monitor capability.
External Display Drive	One SVGA/XGA-compatible analog output port
Display Size	Selected via Windows
	Plug and Play support for DDC1 and DDC2 A and B
	Resolution (Pixels) Colors 640 x 480 256, 64 K, 16.8 M 800 x 600 256, 64 K, 16.8 M 1024 x 768 256, 64 K, 8 M 1280 x 1024 256, 64 K, 8 M
Internal Display	
Classification	Thin Film Transistor (TFT) 10.4 inch active-matrix color LCD display; CCFL backlight; intensity controllable via software
Resolution	800 x 600 pixels
Color Scale	262,144 colors (6-bit RGB)

Table 13: TLA600 front-panel interface

Characteristic	Description
QWERTY Keypad	ASCII keypad to support naming of files, traces, and keyboard equivalents of pointing device inputs for menus
Special Function Knobs	Various functions

Table 14: TLA600 rear-panel interface

Characteristic	Description
Parallel Interface Port (LPT)	36-pin high-density connector supports standard Centronics mode, Enhanced Parallel Port (EPP), or Microsoft high-speed mode (ECP)
Serial Interface Port (COM 1)	9-pin male sub-D connector to support RS-232 serial port
Single USB Ports	One USB (Universal Serial Bus) compliant port
SVGA Output Port (SVGA OUT)	15-pin sub-D SVGA connector
Mouse Port	PS/2 compatible mouse port utilizing a mini DIN connector
Keyboard Port	PS/2 compatible keyboard port utilizing a mini DIN connector
Type I and II PC Card Port	Standard Type I and II PC-compatible PC card slot
Type I, II, and III PC Card Port	Standard Type I, II, and III PC-compatible PC card slot

Table 15: TLA600 AC power source

Characteristic	Description
Source Voltage and Frequency	90–250 V_{RMS}, 45–66 Hz, continuous range CAT II 100–132 V_{RMS}, 360–440 Hz, continuous range CAT II
Fuse Rating	
90 V – 132 V Operation (2 required)	UL198/CSA C22.2 0.25 in × 1.25 in, Fast Blow, 8 A, 250 V
90 V - 250 V Operation (2 required)	IEC 127/Sheet 1 5 mm × 20 mm, Fast Blow, 6.3 A, 250 V
Maximum Power Consumption	600 Watts line power maximum
Steady-State Input Current	6 A_{RMS} maximum
Inrush Surge Current	70 A maximum
Power Factor Correction	Yes
On/Standby Switch and Indicator	Front Panel On/Standby switch, with indicator. The power cord provides main power disconnect.

Table 16: TLA600 cooling

Characteristic	Description
Cooling System	Forced air circulation (negative pressurization) utilizing six fans operating in parallel
Cooling Clearance	2 in (51 mm), sides and rear; unit should be operated on a flat, unobstructed surface

Table 17: TLA600 mechanical characteristics

Characteristic	Description
Overall Dimensions	See Figure 1 for overall chassis dimensions
Weight	Includes empty accessory pouch and front cover
TLA614, TLA624, TLA613, and TLA623	18.1 Kg (40 lbs)
TLA612, TLA622, TLA611, and TLA621	18 Kg (39.75 lbs)
TLA604 and TLA603	17.6 Kg (38.75 lbs)
TLA602 and TLA601	17.5 Kg (38.5 lbs)
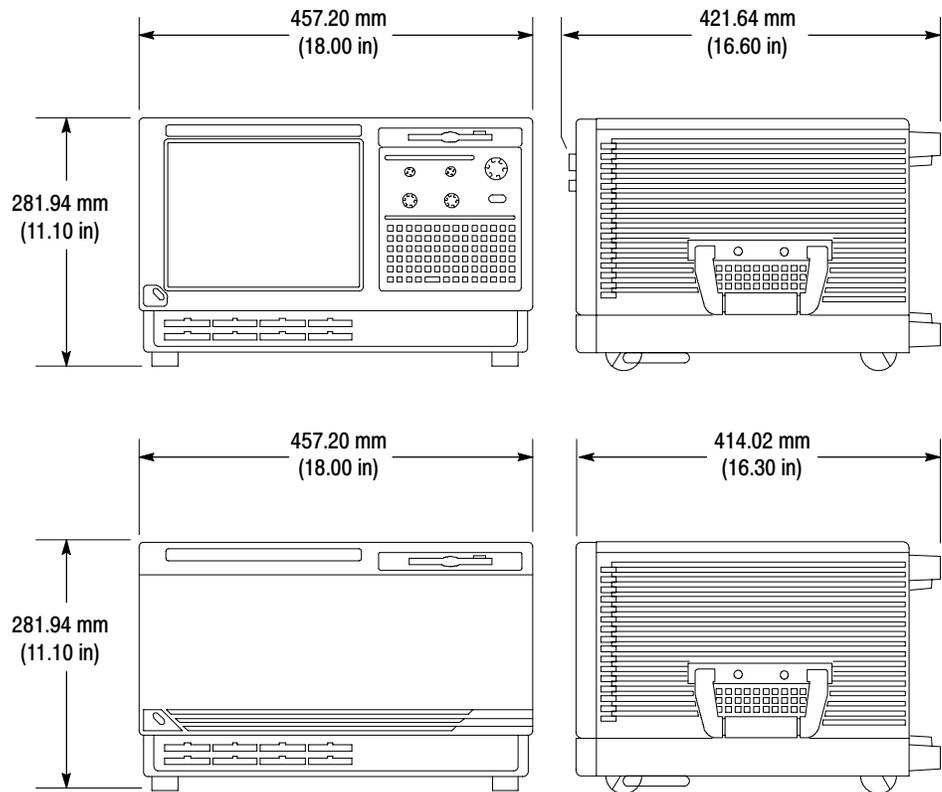
Figure 1: Dimensions of the TLA600 series logic analyzer

TLA5000 Series Logic Analyzer Specifications

Tables 18 through 32 list the specifications for the TLA5000 series logic analyzer.

Table 18: TLA5000 input parameters with probes

Characteristic	Description
✓ Threshold Accuracy	±100 mV
Threshold range and step size	Settable from +4.5 V to –2 V in 5 mV steps
Threshold channel selection	16 threshold groups assigned to channels. P6417, P6418 and P6419 probes have two threshold settings, one for the clock/qualifier channel and one for the data channels. P6434 probes have four threshold settings, one for each of the clock/qualifier channels and two for the data channels (one per 16 data channels).
✓ Channel-to-channel skew	≤ 1 ns maximum
Channel-to-channel skew (Typical)	≤ 0.9 ns
Sample uncertainty	
Asynchronous:	Sample period
Synchronous:	125 ps
Probe input resistance (Typical)	20 kΩ
Probe input capacitance: P6417, P6434 (Typical)	2 pF
Probe input capacitance: P6418 (Typical)	1.4 pF data channels 2 pF CLK/Qual channels
P6419 input capacitance: P6419 (Typical)	< 0.7 pF
Minimum slew rate (Typical)	0.2 V/ns
Maximum operating signal	6.0 V_{p-p} –3.5 V absolute input voltage minimum 6.5 V absolute input voltage maximum
Probe overdrive: P6417, P6418, P6419 P6434	±250 mV or ±25% of signal swing minimum required beyond threshold, whichever is greater ±300 mV or ±25% of signal swing minimum required beyond threshold, whichever is greater ±4 V maximum beyond threshold
Maximum nondestructive input signal to probe	±15 V

Table 18: TLA5000 input parameters with probes (Cont.)

Characteristic	Description
Minimum input pulse width signal (single channel) (Typical)	1.5 ns (P6434) 1.25 ns (P6417, P6418, P6419)
Delay time from probe tip to module input probe connector (Typical)	7.33 ns ±100ps

Table 19: TLA5000 timing latencies

Characteristic	Description
System Trigger and External Signal Input Latencies[1] (Typical)	
External System Trigger Input to LA Probe Tip	–594 ns
External Signal Input to LA Probe Tip via Signal 3, 4	–594 ns + Clk
External Signal Input to LA Probe Tip via Signal 1, 2[2]	–594 ns + Clk
System Trigger and External Signal Output Latencies (Typical)	
LA Probe Tip to External System Trigger Out[3]	760 ns + SMPL
LA Probe Tip to External Signal Out via Signal 3, 4[3]	
OR function	760 ns + SMPL
AND function	760 ns + SMPL
LA Probe Tip to External Signal Out via Signal 1, 2[2, 3]	
normal function	760 ns + SMPL
inverted logic on backplane	760 ns + SMPL

[1]   All system trigger and external signal input latencies are measured from a falling-edge transition (active true low) with signals measured in the wired-OR configuration.

[2]   Signals 1 and 2 (ECLTRG0, 1) are limited to a "broadcast" mode of operation, where only one source is allowed to drive the signal node at any one time. That single source may be utilized to drive any combination of destinations.

[3]   SMPL represents the time from the event at the probe tip inputs to the next valid data sample. In the Normal Internal clock mode, this represents the delta time to the next sample clock. In the MagniVu Internal clock mode, this represents 500 ps or less. In the External clock mode, this represents the time to the next master clock generated by the setup of the clocking state machine, the system-under-test supplied clocks, and the qualification data.

Table 20: TLA5000 external signal interface

Characteristic	Description
System Trigger Input	TTL compatible input via rear panel mounted BNC connectors
Input Levels V_{IH} V_{IL}	TTL compatible input $\geq$ 2.0 V $\leq$ 0.8 V
Input Mode	Falling edge sensitive, latched (active low)
Minimum Pulse Width	12 ns
Active Period	Accepts system triggers during valid acquisition periods via real-time gating, resets system trigger input latch between valid acquisition periods.
Maximum Input Voltage	0 to +5 V peak
External Signal Input	TTL compatible input via rear panel mounted BNC connectors
Input Destination	Signal 1, 2, 3, 4
Input Levels V_{IH} V_{IL}	TTL compatible input $\geq$ 2.0 V $\leq$ 0.8 V
Input Mode	Active (true) low, level sensitive
Input Bandwidth[1] Signal 1, 2, 3, 4	50 MHz square wave minimum
Active Period	Accepts signals during valid acquisition periods via real-time gating.
Maximum Input Voltage	0 to +5 V peak
System Trigger Output	TTL compatible output via rear panel mounted BNC connectors
Source Mode	Active (true) low, falling edge latched
Active Period	Outputs system trigger state during valid acquisition period, resets system trigger output to false state between valid acquisitions.
Output Levels V_{OH} V_{OL}	50 Ω back terminated TTL-compatible output $\geq$4 V into open circuit $\geq$ 2 V into 50 Ω to ground $\leq$ 0.7 V sinking 10 mA
Output Protection	Short-circuit protected (to ground)
External Signal Output	TTL compatible outputs via rear panel mounted BNC connectors
Source Selection	Signal 1, 2, 3, 4, or 10 MHz clock
Output Modes Level Sensitive	User definable Active (true) low or active (true) high
Output Levels V_{OH} V_{OL}	50 Ohm back terminated TTL output $\geq$ 4 V into open circuit $\geq$ 2 V into 50 Ω to ground $\leq$ 0.7 V sinking 10 mA
Output Bandwidth[1] Signal 1, 2, 3, 4	50 MHz square wave minimum

Table 20: TLA5000 external signal interface (Cont.)

Characteristic	Description
Active Period	Outputs signals during valid acquisition periods, resets signals to false state between valid acquisitions. Outputs 10 MHz clock continuously
Output Protection	Short-circuit protected (to ground)

[1]   **The Output Bandwidth specification only applies to signals from the modules; it does not apply to signals applied to the External Signal Input and sent back to the External Signal Output.**

Table 21: TLA5000 channel width and depth

Characteristic	Description	
Number of channels	Product	Channels
	TLA5201	32 data and 2 clock
	TLA5202	64 data and 4 clock
	TLA5203	96 data, 4 clock, and 2 qualifier
	TLA5204	128 data, 4 clock, and 4 qualifier
Acquisition memory depth	Product	Memory depth
	TLA520X	512 K or optionally either 2 or 8 M samples[1]

[1]   **PowerFlex options**

Table 22: TLA5000 clocking

Characteristic	Description	
Asynchronous clocking		
✓ Internal sampling period[1]	500 ps to 50 ms in a 1-2-5 sequence. Storage control can be used to only store data when it has changed (transitional storage)	
	2 ns minimum for all channels 1 ns minimum for half channels (using 2:1 demultiplex mode) 0.5 ns minimum for quarter channels (using 4:1 demultiplex mode)	
✓ Minimum recognizable word[2] (across all channels)	Channel-to-channel skew + sample uncertainty	
	Example: for a P6419, or P6434 Probe and a 2 ns sample period = 1 ns + 2 ns = 3 ns	
Synchronous clocking		
Number of clock channels[3]	Product	Clock channels
	TLA5201	2
	TLA5202	4
	TLA5203	4
	TLA5204	4
Number of qualifier channels[4]	Product	Qualifier channels
	TLA5201	0
	TLA5202	0
	TLA5203	2
	TLA5204	4
✓ Setup and hold window size (data and qualifiers)	Maximum window size = Maximum channel-to-channel skew + (2 x sample uncertainty) + Margin = 1.875 ns	
Setup and hold window size (data and qualifiers) (Typical)	Channel-to-channel skew (*typical*) + (2 x sample uncertainty) = 1.5 ns	
Setup and hold window range	For each channel, the setup and hold window can be moved from +8.0 ns (Ts) to –8.0 ns (Ts) in 0.125 ns steps (setup time). Hold time follows the setup time by the setup and hold window size.	
✓ Maximum synchronous clock rate	235 MHz in full speed mode (4.25 ns minimum between active clock edges)	

Table 22: TLA5000 clocking (Cont.)

Characteristic	Description
2X Demux clocking	
TLA5203 TLA5204	Any individual channel may be demultiplexed with its partner channel. Channels demultiplex as folllows: A3(7:0) to/from D3(7:0) A2(7:0) to/from D2(7:0) A1(7:0) to/from D1(7:0) A0(7:0) to/from D0(7:0) C3(7:0) to/from C1(7:0) C2(7:0) to/from C0(7:0) E3(7:0) to/from E1(7:0) TLA5204 only E2(7:0) to/from E0(7:0) TLA5204 only CK3 to/from Q2 TLA5204 only CK2 to/from Q3) TLA5204 only CK1 to/from Q0 CK0 to/from Q1
TLA5201 TLA5202	Any individual channel may be demultiplexed with its partner channel. Channels demultiplex as folllows: A3(7:0) to/from C3(7:0) A2(7:0) to/from C2(7:0) A1(7:0) to/from D1(7:0) TLA5202 only A0(7:0) to/from D0(7:0) TLA5202 only
Time between Demultiplex clock edges (Typical)	Same limitations as normal synchronous acquisition
4X Demux clocking	
TLA5203 TLA5204	Unlike 2X demultiplexing, the channels within a group of four cannot arbitrarily drive the others. E3(7:0) to E2(7:0), E1(7:0), E0(7:0) TLA5204 only A3(7:0) to A2(7:0), D3(7:0), D2(7:0) A1(7:0) to A0(7:0), D1(7:0), D0(7:0) C3(7:0) to C2(7:0), C1(7:0), C0(7:0) CK3 to CK2, Q3, Q2 TLA5204 only CK1 to CK0, Q1, Q0
TLA5201 TLA5202	Unlike 2X demultiplexing, the channels within a group of four cannot arbitrarily drive the others. A1(7:0) to A0(7:0), D1(7:0), D0(7:0) TL:A5202 only C3(7:0) to C2(7:0), A3(7:0), A2(7:0)
Time between Demultiplex clock edges (Typical)	Same limitations as normal synchronous acquisition

Table 22: TLA5000 clocking (Cont.)

Characteristic	Description
Clocking state machine	
Pipeline delays	Each channel can be programmed with a pipeline delay of 0 through 7 active clock edges.

[1]   It is possible to use storage control and only store data when it has changed (transitional storage).

[2]   Applies to asynchronous clocking only. Setup and hold window specification applies to synchronous clocking only.

[3]   Any or all of the clock channels may be enabled. For an enabled clock channel, either the rising, falling, or both edges can be selected as the active clock edges. The clock channels are stored.

[4]   All qualifier channels are stored. For custom clocking there are an additional 4 qualifier channels on C2 3:0 regardless of channel width.

Table 23: TLA5000 trigger system

Characteristic	Description
Triggering Resources	
Word/Range recognizers	16 word recognizers. The word recognizers can be combined to form full width, double bounded, range recognizers. The following selections are available: 16 word recognizers 0 range recognizers 13 word recognizers 1 range recognizer 10 word recognizers 2 range recognizers 7 word recognizers 3 range recognizers 4 word recognizers 4 range recognizers
Range recognizer channel order	From most-significant probe group to least-significant probe group: C3 C2 C1 C0 E3 E2 E1 E0 A3 A2 D3 D2 A1 A0 D1 D0 Q3 Q2 Q1 Q0 CK3 CK2 CK1 CK0 Missing channels for modules with fewer than 136 channels are omitted.
Glitch detector[1,2]	Channel groups can be enabled to detect glitches. Glitches are subject to pulse width variations of up to ±125 ps
Minimum detectable glitch pulse width (Typical)	1.25 ns (single channel with P6434 probe) 1.0 ns (P6417, P6418, P6419 probe)
Setup and hold violation detector[1,3]	Any channel can be enabled to detect a setup or hold violation. The range is from 8.0 ns before the clock edge to 8.0 ns after the clock edge in 0.125 ns steps. The channel setup and hold violation size can be individually programmed. The range can be shifted towards the positive region by 0 ns, 4 ns, or 8 ns. With a 0 ns shift, the range is +8 ns to −8 ns; with a 4 ns shift, the range is +12 ns to −4 ns; with an 8 ns shift, the range is +16 ns to 0 ns. The sample point selection region is the same as the setup and hold window. Any setup value is subject to variation of up to the channel skew specification. Any hold value is subject to variation of up to the channel skew specification.

Table 23: TLA5000 trigger system (Cont.)

Characteristic	Description
Transition detector[1]	16 transition detectors.
	Any channel group can be enabled or disabled to detect a rising transition, a falling transition, or both rising and falling transitions between the current valid data sample and the previous valid data sample.
Counter/Timers	2 counter/timers, 51 bits wide, can be clocked up to 500 MHz. Maximum count is 2^{51}–1. Maximum time is 4.5×10^{6} seconds or 52 days.
	Counters and timers can be set, reset, or tested and have zero reset latency.
External Signal In[1]	A backplane input signal.
External Trigger In	A backplane input signal that causes both the main acquisition and the MagniVu acquisition to trigger if they are not already triggered.
Active trigger resources	16 maximum (excluding counter/timers)
	Word recognizers are traded off one-by-one as External Signal In, glitch detection, setup and hold detection, or transition detection resources are added.
Trigger States	16
✔ Trigger State sequence rate	Same rate as valid data samples received, 500 MHz maximum.
Trigger Machine Actions	
Main acquisition trigger	Triggers the main acquisition memory.
Main trigger position	Trigger position is programmable to any data sample (2 ns boundaries).
MagniVu™ acquisition trigger	Triggering of MagniV memory is controlled by the main acquisition trigger machine.
MagniVu™ trigger position	The MagniV trigger position is programmable within 2 ns boundaries and separate from the main acquisition memory trigger position.
Increment & decrement counter	Either of the two counter/timers used as counters can be increased or decreased.
Reloadable word recognizer	Loads the current acquired data sample into the reference value of the word recognizer via a trigger machine action. All data channels are loaded into their respective word recognizer reference register on a one-to-one manner.
Reloadable word recognizer latency	378 ns
Start/Stop timer	Either of the two counter/timers used as timers can be started or stopped.
Reset counter/timer	Either of the two counter/timers can be reset.
	When a counter/timer is used as a timer and is reset, the timer continues from the started or stopped state that it was in prior to the reset.
Signal out	A signal sent to the backplane to be used by other instruments.
Trigger out	A trigger out signal sent to the backplane to trigger other instruments.

Table 23: TLA5000 trigger system (Cont.)

Characteristic	Description
Storage Control	
Global storage	Storage is allowed only when a specific condition is met. This condition can use any of the trigger machine resources except for the counter/timers. Storage commands defined in the current trigger state will override the global storage control. Global storage can be used to start the acquisition with storage initially turned on (default) or turned off.
By event	Storage can be turned on or off; only the current sample can be stored. The event storage control overrides any global storage commands.
Block storage	When enabled, 31 samples are stored before and after the valid sample. Not allowed when glitch storage or setup and hold violation is enabled.
Glitch violation storage	The acquisition memory can be enabled to store glitch violation information with each data sample when asynchronous clocking is used. The probe data storage size is reduced by one half (the other half holds the violation information). The fastest asynchronous clocking rate is reduced to 4 ns.
Setup and hold violation storage	The acquisition memory can be enabled to store setup and hold violation information with each data sample when synchronous clocking is used. The probe data storage size is reduced by one half (the other half holds the violation information). The maximum clock rate in this mode is 235 MHz.

[1]   Each use of External Signal In, glitch detector, setup and hold violation detector, or transition detector requires a trade-off of one word recognizer resource.

[2]   Any glitch is subject to pulse width variation of up to the channel-to-channel skew specification + 0.25 ns.

[3]   Any setup value is subject to variation of up to the channel skew specification. Any hold value is subject to variation of the channel skew specifications.

Table 24: TLA5000 MagniVu™ feature

Characteristic	Description
MagniVu memory depth	16,000 samples per channel
MagniVu sampling period	Data is asynchronously sampled and stored every 125 ps in a separate high resolution memory. The storage speed may be changed (by software) to 250 ps, 500 ps, or 1000 ps so that MagniVu memory covers more time at a lower resolution.

Table 25: TLA5000 Data handling

Characteristic	Description
Nonvolatile memory retention time (Typical)	Battery is integral to the NVRAM. Battery life is > 10 years.

Table 26: TLA5000 internal controller

Characteristic	Description
Operating System	Microsoft Windows
Microprocessor	Intel Celeron, 2 GHz
Main Memory	PC2100 DDR SDRAM
Style	184 pin DIMM, 2 Sockets
Speed	100 MHz
Installed configuration	512 MB loaded in one socket
Real-Time Clock and CMOS Setups, Plug & Play NVRAM Retention Time	Battery life is typically > 3 years when the logic analyzer is not connected to line voltage. When connected to line voltage the life of the battery is extended. Lithium battery, CR2032
Hard Disk Drive	Standard PC compatible IDE (Integrated Device Electronics) hard disk drive residing on an EIDE interface.
Size	Formatted capacity 80 GByte Continually subject to change due to the fast-moving PC component environment. These storage capacities valid at product introduction.
CD-RW Drive	Standard PC compatible IDE (Integrated Device Electronics) CD-RW drive residing on an EIDE interface. Continually subject to change due to the fast-moving PC component environment.
Floppy Disk Drive	Standard 3.5 inch 1.44-MB PC compatible high-density, double-sided floppy disk drive.

Table 27: TLA5000 display system

Characteristic	Description
Classification	Standard PC graphics accelerator technology (bitBLT-based); capable of supporting both internal color LCD display and external color SVGA/XGA monitor.
Display Memory	SDRAM-onboard the ATI Mobility I video controller clocked up to 100 MHz.
Size	8 MB
Display Selection	Both front panel and external displays can be used simultaneously, each with independent resolutions. Supports Windows dual-monitor capability.
External Display Drive	Two XGA-compatible analog output ports
Primary Display Size (RAGE M1 chip)	Selected via Windows Resolution (Pixels) Colors 1024 x 768 256, 64 K, 16.8 M
Secondary Display Size (845GV chip)	Selected via Windows Resolution (Pixels) Colors 640 x 480 256, 64 K, 16.8 M 800 x 600 256, 64 K, 16.8 M 1024 x 768 256, 64 K, 16.8 M 1280 x 1024 256, 64 K, 16.8 M 1600 x 1200 256, 64 K, 16.8 M 1920 x 1440 256, 64K
Internal Display	
Classification	Thin Film Transistor (TFT) 10.4 inch active-matrix color LCD display; CCFL backlight; intensity controllable via software.
Resolution	1024 x 768 pixels
Color Scale	256K

Table 28: TLA5000 front-panel interface

Characteristic	Description
QWERTY Keypad	ASCII keypad to support naming of files, traces, and keyboard equivalents of pointing device inputs for menus.
Special Function Knobs	Various functions

Table 29: TLA5000 rear-panel interface

Characteristic	Description
Parallel Interface Port (LPT)	25-pin sub-D Parallel Port Connector, Extended Parallel Port (EPP), or Enhanced Capabilities Port (ECP)
Serial Interface Port (COM 1)	9-pin male sub-D connector to support RS-232 serial port
Two USB Ports	Two USB 2.0 (Universal Serial Bus) compliant ports
SVGA Output Ports (SVGA OUT)	15-pin sub-D SVGA connectors (two each, one Primary, one Secondary)
Mouse Port	PS/2 compatible mouse port utilizing a mini DIN connector
Keyboard Port	PS/2 compatible keyboard port utilizing a mini DIN connector

Table 30: TLA5000 AC power source

Characteristic	Description
Source Voltage and Frequency	100–240 VAC ±10%, 47–63 Hz, continuous range CAT II
Maximum Power Consumption	225 Watts line power maximum
Steady-State Input Current	4 A_{RMS} maximum
Inrush Surge Current	65 A maximum
Power Factor Correction	Yes
On/Standby Switch and Indicator	Front Panel On/Standby switch, with indicator. The power cord provides main power disconnect.

Table 31: TLA5000 cooling

Characteristic	Description
Cooling System	Forced air circulation (negative pressurization) utilizing two fans operating in parallel
Cooling Clearance	51 mm (2 in), sides and rear; unit should be operated on a flat, unobstructed surface

Table 32: TLA5000 mechanical characteristics

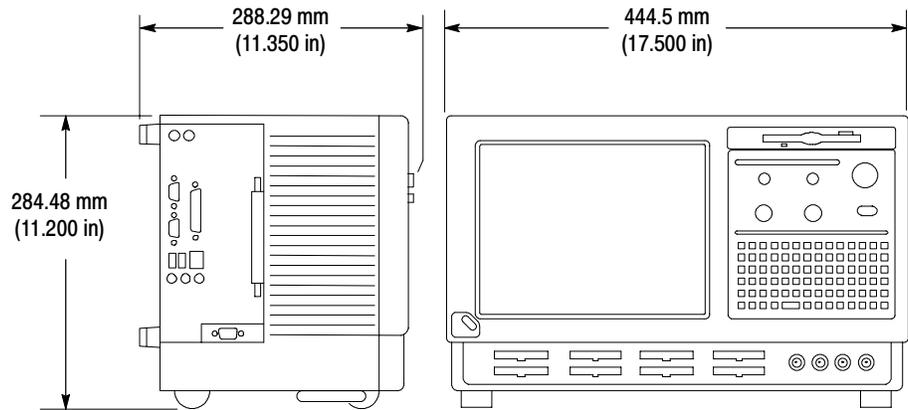| Characteristic	Description
Overall Dimensions	See Figure 1 for overall chassis dimensions
Weight	Includes empty accessory pouch and front cover
TLA5201	11.8 Kg (25 lb 15 oz)
TLA5202	11.85 Kg (26 lb 2 oz)
TLA5203	11.9 Kg (26 lb 4 oz)
TLA5204	12 Kg (26 lb 7 oz)

Figure 2: Dimensions of the TLA5000 series logic analyzer

TLA700 System Specifications

Tables 33 through 35 list the specifications common to the TLA715, TLA714, TLA720, and TLA721 logic analyzers. Detailed specifications for the individual logic analyzers begin on page 38.

Table 33: TLA700 Backplane interface

Characteristic	Description
Slots	
Portable mainframe	4
Benchtop mainframe	10 (three slots taken up by the controller module)
Expansion mainframe	13
✔ CLK10 Frequency	10 MHz ±100 PPM
Relative Time Correlation Error[1,2] (Typical)	
TLA7Lx/Mx/Nx/Px/Qx to TLA7Lx/Mx/Nx/Px/Qx "MagniVu" data	2 ns
TLA7Axx/TLA7NAx to TLA7AxxTLA7NAx "MagniVu" data	2 ns
TLA7Axx/TLA7NAx to TLA7Lx/Mx/Nx/Px/Qx "MagniVu" data	−3 ns
TLA7Lx/Mx/Nx/Px/Qx to TLA7Lx/Mx/Nx/Px/Qx "normal" data using an internal clock	1 TLA7Lx/Mx/Nx/Px/Qx sample − 0.5 ns
TLA7Axx/TLA7NAx to TLA7Axx "normal" data using an internal clock	1 TLA7Axx/TLA7NAx sample − 0.5 ns
TLA7Axx/TLA7NAx to TLA7Lx/Mx/Nx/Px/Qx "normal" data using an internal clock	1 TLA7Lx/Mx/Nx/Px/Qx sample − 0.5 ns
TLA7Lx/Mx/Nx/Px/Qx to TLA7Lx/Mx/Nx/Px/Qx "normal" data using an external clock	2 ns
TLA7Axx/TLA7NAx to TLA7Axx/TLA7NAx "normal" data using an external clock	2 ns
TLA7Axx/TLA7NAx to TLA7Lx/Mx/Nx/Px/Qx "normal" data using an external clock	4 ns

Table 33: TLA700 Backplane interface (Cont.)

Characteristic	Description
TLA7Lx/Mx/Nx/Px/Qx "MagniVu" to DSO data	3 ns
TLA7Axx/TLA7NAx "MagniVu" to DSO data	2 ns
TLA7Lx/Mx/Nx/Px/Qx to DSO "normal" data using an internal clock[3]	1 TLA7Lx/Mx/Nx/Px/Qx sample + 2 ns
TLA7Axx/TLA7NAx to DSO "normal" data using an internal clock[3]	1 TLA7Axx/TLA7NAx sample + 2 ns
TLA7Lx/Mx/Nx/Px/Qx to DSO "normal" data using an external clock[3]	3 ns
TLA7Axx/TLA7NAx to DSO "normal" data using an external clock[3]	2 ns
DSO to DSO[3]	3 ns

[1]   Includes typical jitter, slot-to-slot skew, and probe-to-probe variations to provide a "typical" number for the measurement. Assumes standard accessory probes are utilized.

[2]   For time intervals longer than 1 μs between modules, add 0.01% of the difference between the absolute time measurements to the relative time correlation error to account for the inaccuracy of the CLK10 source.

[3]   The DSO module time correlation is measured at the maximum sample rate on one channel only.

Table 34: TLA700 Backplane latencies

Characteristic	Portable mainframe and benchtop mainframe	Expansion mainframe
System trigger and external signal input latencies[2] (Typical)		
External system trigger input to TLA7Lx/Mx/Nx/Px/Qx probe tip[4]	-266 ns	-230 ns
External system trigger input to TLA7Axx probe tip[4]	-653 ns	-617 ns
External signal input to TLA7Lx/Mx/Nx/Px/Qx probe tip via Signal 3, 4[5]	-212 ns + Clk	-176 ns + Clk
External signal input to TLA7Axx/TLA7NAx probe tip via Signal 3, 4[5]	-212 ns + Clk	-176 ns + Clk
External signal input to TLA7Lx/Mx/Nx/Px/Qx probe tip via Signal 1, 2[5, 6]	-634 ns + Clk	-596 ns + Clk
External signal input to TLA7Axx/TLA7NAx probe tip via Signal 1, 2[5, 6]	-636 ns + Clk	-615 ns + Clk
External system trigger input to DSO probe tip[4]	-25 ns	11 ns
System trigger and external signal output latencies[1] *(Typical)*		
TLA7Lx/Mx/Nx/Px/Qx probe tip to external system trigger out	376 ns + SMPL	412 ns + SMPL
TLA7Axx/TLA7NAx probe tip to external system trigger out	794 ns + SMPL	830 ns + SMPL
TLA7Lx/Mx/Nx/Px/Qx probe tip to external signal out via Signal 3, 4[3]		
OR function	366 ns + SMPL	402 ns + SMPL
AND function	379 ns + SMPL	415 ns + SMPL
TLA7Axx/TLA7NAx probe tip to external signal out via Signal 3, 4[3]		
OR function	792 ns + SMPL	828 ns + SMPL
AND function	800 ns + SMPL	836 ns + SMPL
TLA7Lx/Mx/Nx/Px/Qx probe tip to external signal out via Signal 1, 2[3, 6]		
normal function	364 ns + SMPL	385 ns + SMPL
inverted logic on backplane	364 ns + SMPL	385 ns + SMPL
TLA7Axx/TLA7NAx probe tip to external signal out via Signal 1, 2[3, 6]		
normal function	796 ns + SMPL	817 ns + SMPL
inverted logic on backplane	796 ns + SMPL	817 ns + SMPL

Table 34: TLA700 Backplane latencies (Cont.)

Characteristic	Portable mainframe and benchtop mainframe	Expansion mainframe
DSO probe tip to external system trigger out	68 ns	104 ns
DSO Probe tip to external signal out via Signal 3, 4[3]		
OR function	65 ns	101 ns
AND function	75 ns	111 ns
DSO probe tip to external signal out via Signal 1, 2[3,6]		
normal function	68 ns	89 ns
inverted logic on backplane	71 ns	92 ns
Inter-module latencies (Typical)		
TLA7Lx/Mx/Nx/Px/Qx to DSO inter-module system trigger[1,4]	358 ns + SMPL	394 ns + SMPL
TLA7Axx/TLA7NAx to DSO inter-module system trigger[1,4]	772 ns + SMPL	808 ns + SMPL
TLA7Lx/Mx/Nx/Px/Qx to TLA7Lx/Mx/Nx/Px/Qx inter-module system trigger[1,4]	66 ns + SMPL	102 ns + SMPL
TLA7Axx/TLA7NAx to TLA7Lx/Mx/Nx/Px/Qx inter-module system trigger[1,4]	479 ns + SMPL	515 ns + SMPL
TLA7Axx/TLA7NAx to TLA7Axx/TLA7NAx inter-module system trigger[1,4]	116 ns + SMPL	152 ns + SMPL
TLA7Lx/Mx/Nx/Px/Qx to DSO inter-module ARM[1]	360 ns + SMPL	396 ns + SMPL
TLA7Axx/TLA7NAx to DSO inter-module ARM[1]	779 ns + SMPL	815 ns + SMPL
TLA7Lx/Mx/Nx/Px/Qx to TLA7Lx/Mx/Nx/Px/Qx inter-module ARM[1,5]	108 ns + SMPL + Clk	144 ns + SMPL + Clk
TLA7Axx/TLA7NAx to TLA7Lx/Mx/Nx/Px/Qx inter-module ARM[1,5]	479 ns + SMPL + Clk	533 ns + SMPL + Clk
TLA7Axx/TLA7NAx to TLA7Axx inter-module ARM[1,5]	111 ns + SMPL + Clk	147 ns + SMPL + Clk
TLA7Lx/Mx/Nx/Px/Qx to TLA7Lx/Mx/Nx/Px/Qx inter-module via Signal 1, 2[1,5,6]	116 ns + SMPL + Clk	137 ns + SMPL + Clk
TLA7Axx/TLA7NAx to TLA7Axx inter-module via Signal 1, 2[1,5,6]	113 ns + SMPL + Clk	134 ns + SMPL + Clk
TLA7Axx/TLA7NAx to TLA7Lx/Mx/Nx/Px/Qx inter-module via Signal 1, 2[1,5,6]	534 ns + SMPL + Clk	555 ns + SMPL + Clk
TLA7Lx/Mx/Nx/Px/Q to TLA7Lx/Mx/Nx/Px/Qx inter-module via Signal 3, 4[1,5]	116 ns + SMPL + Clk	152 ns + SMPL + Clk
TLA7AxxTLA7NAx to TLA7Axx inter-module via Signal 3, 4[1,5]	124 ns + SMPL + Clk	160 ns + SMPL + Clk

Table 34: TLA700 Backplane latencies (Cont.)

Characteristic	Portable mainframe and benchtop mainframe	Expansion mainframe
TLA7Axx/TLA7NAx to TLA7Lx/Mx/Nx/Px/Qx inter-module via Signal 3, 4[1,5]	545 ns + SMPL + Clk	581 ns + SMPL + Clk
TLA7Lx/Mx/Nx/Px/Qx to TLA7Axx/TLA7NAx inter-module System Trigger[1,4]	-287 ns + SMPL	-251 ns + SMPL
DSO to TLA7Lx/Mx/Nx/Px/Qx inter-module System Trigger[4]	-240 ns	-204 ns
DSO to TLA7Axx/TLA7NAx inter-module System Trigger[4]	-598 ns	-562 ns
DSO to DSO inter-module System Trigger[4]	50 ns	86 ns
TLA7Lx/Mx/Nx/Px/Qx to TLA7Axx/TLA7NAx inter-module ARM[1,5]	-300 ns + SMPL + Clk	-264 ns + SMPL + Clk
DSO to TLA7Lx/Mx/Nx/Px/Qx inter-module ARM[5]	-192 ns + Clk	-156 ns + Clk
DSO to TLA7Axx/TLA7NAx inter-module ARM[5]	-600 ns + Clk	-564 ns + Clk
DSO to DSO inter-module ARM	59 ns	95 ns
DSO to TLA7Lx/Mx/Nx/Px/Qx inter-module via Signal 1, 2[5,6]	-179 ns + Clk	-158 ns + Clk
TLA7Lx/Mx/Nx/Px/Qx to TLA7Axx/TLA7NAx inter-module via Signal 1, 2[1,5,6]	-294 ns + SMPL + Clk	-273 ns + SMPL + Clk
DSO to TLA7Axx/TLA7NAx inter-module via Signal 1, 2[5,6]	-598ns + Clk	-577 ns + Clk
TLA7Lx/Mx/Nx/Px/Qx to TLA7Axx/TLA7NAx inter-module via Signal 3, 4[1,5]	-294 ns + SMPL + Clk	-258 ns + SMPL + Clk

Table 34: TLA700 Backplane latencies (Cont.)

Characteristic	Portable mainframe and benchtop mainframe	Expansion mainframe
DSO to TLA7Lx/Mx/Nx/Px/Qx inter-module via Signal 3, 4[5]	–184 ns + Clk	–148 ns + Clk
DSO to TLA7Axx/TLA7NAx inter-module via Signal 3, 4[5]	–598 ns + Clk	–562 ns + Clk

[1] SMPL represents the time from the event at the probe tip inputs to the next valid data sample of the LA module. In the Normal Internal clock mode, this represents the delta time to the next sample clock. In the MagniVu Internal clock mode, this represents 500 ps or less. In the External clock mode, this represents the time to the next master clock generated by the setup of the clocking state machine, the system-under-test supplied clocks, and the qualification data.

[2] All system trigger and external signal input latencies are measured from a falling-edge transition (active true low) with signals measured in the wired-OR configuration.

[3] All signal output latencies are validated to the rising edge of an active (true) high output.

[4] In the Waveform window, triggers are always marked immediately except when delayed to the first sample. In the Listing window, triggers are always marked on the next sample period following their occurrence.

[5] "Clk" represents the time to the next master clock at the destination logic analyzer. In the asynchronous (or internal) clock mode, this represents the delta time to the next sample clock beyond the minimum asynchronous rate of 4 ns. In the synchronous (or external) clock mode, this represents the time to the next master clock generated by the setup of the clocking state machine and the supplied system under test clocks and qualification data.

[6] Signals 1 and 2 are limited to a "broadcast" mode of operation, where only one source is allowed to drive the signal node at any one time. That single source may be utilized to drive any combination of destinations.

Table 35: TLA700 External signal interface

Characteristic	Description
System Trigger Input	TTL compatible input via rear panel mounted BNC connectors (portable mainframe) or front panel mounted SMB connectors (benchtop mainframe)
Input Levels V_{IH} V_{IL}	TTL compatible input ≥ 2.0 V ≤ 0.8 V
Input destination	System trigger
Input Mode	Falling edge sensitive, latched (active low)
Minimum Pulse Width	12 ns
Active Period	Accepts system triggers during valid acquisition periods via real-time gating, resets system trigger input latch between valid acquisition periods
Maximum Input Voltage	0 to +5 V peak
External Signal Input	TTL compatible input via rear panel mounted BNC connectors (portable mainframe) or front panel mounted SMB connectors (benchtop mainframe)
Input Destination	Signal 1, 2 Signal 3, 4
Input Levels V_{IH} V_{IL}	TTL compatible input ≥ 2.0 V ≤ 0.8 V
Input Mode	Active (true) low, level sensitive
Input Bandwidth[1] Signal 1, 2 Signal 3, 4	 50 MHz square wave minimum 10 MHz square wave minimum
Active Period	Accepts signals during valid acquisition periods via real-time gating
Maximum Input Voltage	0 to +5 V peak
System Trigger Output	TTL compatible output via rear panel mounted BNC connectors (portable mainframe) or front panel mounted SMB connectors (benchtop mainframe)
Source selection	System trigger
Source Mode	Active (true) low, falling edge latched
Active Period	Outputs system trigger state during valid acquisition period, resets system trigger output to false state between valid acquisitions
Output Levels V_{OH} V_{OL}	50 Ω back terminated TTL-compatible output ≥4 V into open circuit ≥ 2 V into 50 Ω to ground ≤ 0.7 V sinking 10 ma
Output Protection	Short-circuit protected (to ground)

Table 35: TLA700 External signal interface (Cont.)

Characteristic	Description
External Signal Output	TTL compatible outputs via rear panel mounted BNC connectors (portable mainframe) or front panel mounted SMB connectors (benchtop mainframe)
Source Selection	Signal 1, 2 Signal 3, 4 10 MHz clock
Output Modes 　Level Sensitive	User definable Active (true) low or active (true) high
Output Levels 　V_{OH} 　V_{OL}	50 Ω back terminated TTL output 　$\geq$ 4 V into open circuit 　$\geq$ 2 V into 50 Ω to ground 　$\leq$ 0.7 V sinking 10 ma
Output Bandwidth[2] 　Signal 1, 2 　Signal 3, 4	 50 MHz square wave minimum 10 MHz square wave minimum
Active Period	Outputs signals during valid acquisition periods, resets signals to false state between valid acquisitions Outputs 10 MHz clock continuously
Output Protection	Short-circuit protected (to ground)
Intermodule signal line bandwidth	Minimum bandwidth up to which the intermodule signals are specified to operate correctly
Signal 1, 2 Signal 3, 4	50 MHz square wave minimum 10 MHz square wave minimum

[1]　The Input Bandwidth specification only applies to signals to the modules; it does not apply to signals applied to the External Signal Input and sent back to the External Signal Output.

[2]　The Output Bandwidth specification only applies to signals from the modules; it does not apply to signals applied to the External Signal Input and sent back to the External Signal Output.

TLA715 Dual Monitor Portable Mainframe Characteristics

Tables 36 through 43 describe the specifications for the TLA715 Dual Monitor Portable Mainframe.

Table 36: TLA715 Internal controller

Characteristic	Description
Operating system	Microsoft Windows 2000
Microprocessor	Intel Pentium PC-AT configuration with an Intel 815E chip-set and a 733 MHz Pentium III processor
Main memory	SDRAM
Style	144 pin SO DIMM, 2 sockets, gold plated, 1.25-inch (3.175 cm) maximum height
Speed	133 MHz
Available configurations	32, 64, 128, 256 MByte per SO DIMM
Installed configurations	512 MB with both sockets loaded
Cache memory	256 KByte Level 2 (L2) write-back cache
Flash BIOS	256 KByte
Real-time clock and CMOS setups NVRAM	Real-time clock/calendar, standard and advanced PC CMOS setups; see BIOS specification
RTC, CMOS setup, & PNP NVRAM retention time (typical)	> 10 years battery life, lithium battery
Floppy disk drive	Standard 3.5 inch 1.44-MB PC compatible high-density, double-sided floppy disk drive, 500 Kbits/sec transfer rate
Bootable replaceable hard disk drive	Standard PC compatible IDE (Integrated Device Electronics) hard disk drive residing on an EIDE interface.
Size	40 GB Continually subject to change due to the fast-moving PC component environment. These storage capacities valid at product introduction.
Interface	ATA −5/enhanced IDE (EIDE)
Average seek time	Read, 12 ms
Average latency	7/14 ms
I/O data transfer rate	33.3 MBytes/sec maximum (U-DMA mode 2)
Cache buffer	2 MBytes (30 GB) /512 KBytes (10GB)
CD-RW drive	Standard PC compatible IDE (Integrated device Electronics) 8x-8x-24x CD-RW drive residing on an IDE interface. Continually subject to change due to the fast-moving PC component environment.

Table 37: TLA715 display system

Characteristic	Description
Classification	Standard PC graphics-accelerator technology capable of supporting both internal color LCD display and two external color VGA, SVGA, or XGA monitors
Display memory	4 MB SDRAM clocked up to 100 MHz, no external video memory
Display selection	Hardware sense of external SVGA monitor during BIOS boot sequence; defaults to internal color LCD display (indicated by two beeps); automatically switches to external SVGA monitor, if attached (indicated by one beep).

Dual (simultaneous) display of external SVGA monitor and internal color LCD is possible via special CMOS "simulscan" setup, as long as internal and external displays operate at same resolution (limited to 800x600 on current LCD) and display rates (simulscan mode indicated by three beeps).

Four beeps during the BIOS boot indicates a monochrome LCD was found (not supported). Five beeps indicates no recognizable LCD or external monitor was found.

Dynamic Display Configuration 1 (DDC1) support for external SVGA monitor is provided. |
External display drive	Two VGA, SVGA, or XGA-compatible analog output ports. Display size is selected via Win2000 display applet.
Display Size (Primary video port with Silicon motion chip)	Resolution (Pixels) Colors Refresh Rates 640 x 480 256, 64 K, 16.8 M 60, 75, 85 800 x 600 265, 64 K, 16.8 M 60, 75, 85 1024 x 768 256, 64 K, 16.8 M 60, 75, 85 1280 x 1024 256, 64 K, 16.8 M 60 1600 x 600 256, 64 K 60 1600 x 1200 256, 64 K 60
(Secondary video port with 815E chip set)	Resolution (Pixels) Colors Refresh Rates 640 x 480 256, 64 K, 16.8 M 60, 75, 85 800 x 600 256, 64 K, 16.8 M 60, 75, 85 1024 x 768 256, 64 K, 16.8 M 60, 75, 85 1280 x 1024 256, 64 K, 16.8 M 60, 75, 80 1600 x 1200 256 60, 75
Internal display	
Classification	TFT (Thin Film Transistor) 26 cm active-matrix color LCD display, CCFL backlight, intensity controllable via software
Resolution	800 X 600, 262, 144 colors with 211.2 mm (8.3 in) by 158.4 mm (6.2 in) of viewing area
Color scale	262, 144 colors (6-bit RGB) with a color gamut of 42% at center to NTSC

Table 38: TLA715 front-panel interface

Characteristic	Description
QWERTY keypad	31-key ASCII keypad to support naming of files, traces, and keyboard equivalents of pointing device inputs for menus
HEX keypad	25-key HEX keypad supporting standard DSO and LA entry functions
Special function knobs	
Multi-function knob	Various increment/decrement functions dependent on screen or window type
Vertical position	Scrolling and positioning dependent on display type
Vertical scale	Scales waveform displays only
Horizontal position	Scrolling and positioning dependent on display type
Horizontal scale	Scales waveform displays only
Integrated pointing device	Vertically mounted Trackball with two keypad control buttons (SELECT and MENU)
USB port	Front panel (lower left-hand side) dual USB connector
Mouse Port	PS/2 compatible pointing device port
Keyboard Port	PS/2 compatible keyboard port

Table 39: TLA715 rear-panel interface

Characteristic	Description
Parallel interface port	36-pin high-density connector supports Output only, Enhanced Parallel Port (EPP), or Microsoft high-speed mode (ECP)
	Complies with IEEE P1284-C/D2 for bi-directional Parallel Peripheral Interface for Personal Computers (draft) style 1284-C
Serial interface port	9-pin male sub-D connector to support RS-232 serial port
SVGA output Port 1 and Port 2	Two 15-pin sub-D SVGA connectors
PC CardBus32 port	Standard Type I, II, III PC-compatible, PC card slot
	Complies with PCMCIA 2.1 and JEIDA 4.1

Table 40: TLA715 AC power source

Characteristic	Description
Source voltage and frequency	90 V_{RMS} to 250 V_{RMS}, 45 Hz to 66 Hz, continuous range CAT II; 100 V_{RMS} to 132 V_{RMS}, 360 Hz to 440 Hz, continuous range CAT II
Fuse rating	
90 V to 250 V operation (159-0046-00)	UL198/CSA C22.2 0.25 in × 1.25 in, Fast Blow, 8 A, 250 V
90 V to 250 V operation (159-0381-00)	IEC 127/Sheet 1 5 mm × 20 mm, Fast Blow, 6.3 A, 250 V
Maximum power consumption	600 W
Steady-state input current	6 A_{RMS} maximum at 90 VAC_{RMS}, 60 Hz or 100 VAC_{RMS}, 400 Hz
Inrush surge current	70 A maximum
Power factor correction	Yes
On/Sleep indicator	Green/yellow front panel LED located next to On/Standby switch provides visual feedback when the On/Off switch is actuated. When the LED is green, the instrument is powered and the processor is not sleeping. When the LED is yellow, the instrument is powered, but the processor is sleeping.
On/Standby switch and indicator	Front panel On/Standby switch. Users can push the switch to power down the instrument without going through the Windows shutdown process; the instrument normally powers down. The power cord provides main power disconnect.

Table 41: TLA715 secondary power

Characteristic	Description			
✓ DC Voltage Regulation (Combined System, voltage available at each slot)	Voltage	Minimum	Nominal	Maximum
	+24 V	23.28 V	24.24 V	25.20 V
	+12 V	11.64 V	12.12 V	12.60 V
	+5 V	4.875 V	5.063 V	5.250 V
	-2 V	-2.10 V	-2.00 V	-1.90 V
	-5.2 V	-5.460 V	-5.252 V	-5.044 V
	-12 V	-12.60 V	-12.12 V	-11.64 V
	-24 V	-25.20 V	-24.24 V	-23.28 V

Table 42: TLA715 cooling

Characteristic	Description
Cooling system	Forced air circulation system with no removable filters using six fans operating in parallel
Pressurization	Negative pressurization system in all chambers including modules
Slot activation	Installing a module activates the cooling for the corresponding occupied slots by opening the airflow shutter mechanism. Optimizes cooling efficiency by only applying airflow to installed modules.
Air intake	Front sides and bottom
Air exhaust	Back rear
Cooling clearance	2 inches (51 mm) front, sides, top, and rear. Prevent blockage of airflow to bottom of instrument by placing on a solid, noncompressable surface; can be operated on rear feet.
Fan speed and operation	All fans operational at half their rated potential and speed (12 VDC)

Table 43: TLA715 mechanical

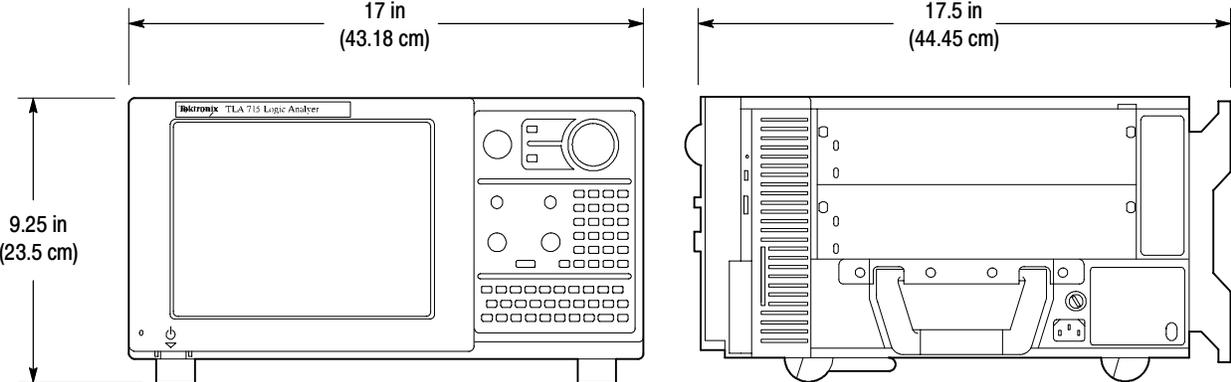| Characteristic	Description
Overall dimensions	(See Figure 4 for overall chassis dimensions) Dimensions are without front feet extended, front cover attached, pouch attached, nor power cord attached.
Height (with feet)	9.25 in (23.5 cm)
Width	17 in (43.18 cm)
Depth	17.5 in (44.45 cm)
Weight	30 lbs 12 oz (13.9 kg) with no modules installed, two dual-wide slot covers, and empty pouch
Shipping configuration	60 lbs 13 oz (27.58 kg) minimum configuration (no modules), with all standard accessories
	86 lbs 9 oz (39.26 kg) full configuration, with two TLA 7P4 modules and standard accessories (including probes and clips)
Acoustic noise level (typical)	42.7 dBA weighted (operator) 37.0 dBA weighted (bystander)
Construction materials	Chassis parts are constructed of aluminum alloy; front panel and trim peaces are constructed of plastic; circuit boards are constructed of glass.
Finish type	Tektronix blue body and Tektronix silver-gray trim and front with black pouch, FDD feet, handle, and miscellaneous trim pieces

Figure 3: Dimensions of TLA715 portable mainframe

TLA714 Portable Mainframe Characteristics

Tables 44 through 51 describe the specifications for the TLA714 Portable Mainframe.

Table 44: TLA714 Internal controller

Characteristic	Description
Operating System	Microsoft Windows
Microprocessor	Intel Pentium PC-AT configuration with a 266 MHz Intel Pentium MMX microprocessor
Main Memory	SDRAM
Style	144 pin SO DIMM, 2 Sockets
Speed	66 MHz
Installed Configurations	Minimum 64 MB loaded in one socket Maximum 128 MB with both sockets loaded
Cache Memory	512 KB Level 2 (L2) write-back cache
Flash BIOS	512 KB Provides PC plug-and-play services with and without Microsoft Windows operating system. Flash based BIOS field upgradable via a floppy disk.
Real-Time Clock and CMOS Setups NVRAM	Real-Time clock/calendar, with typical 10-year life. Standard and advanced PC CMOS setups.
Bootable Replaceable Hard Disk Drive	Standard PC compatible IDE (Integrated device Electronics) hard disk drive residing on an EIDE interface.
Size	Minimum 10 GByte Maximum 30 GByte Continually subject to change due to the fast-moving PC component environment. These storage capacities valid at product introduction.
Interface	ATA 4/Enhanced IDE (EIDE)
Average seek time	Read 13 ms
I/O data-transfer rate	33.3 MB/s max (U-DMA mode 2) (ATA33)
CD-RW Drive	Standard PC compatible IDE (Integrated device Electronics) 8x-8x-24x CD-RW drive residing on an IDE interface Continually subject to change due to the fast-moving PC component environment
Floppy Disk Drive	Standard 3.5 inch 1.44-MB PC compatible high-density, double-sided floppy disk drive

Table 45: TLA714 display system

Characteristic	Description
Classification	Standard PC graphics accelerator technology (bitBLT-based); capable of supporting both internal color LCD display and external color SVGA/XGA monitor
Display Memory	DRAM-based frame-buffer memory
Size	2 MB
Display Selection	Hardware sense of external SVGA monitor during BIOS boot sequence; defaults to internal color LCD display; automatically switches to external SVGA monitor, if attached
	Dual (simultaneous) display of external SVGA monitor and internal color LCD is possible via special "simulscan" CMOS setup, as long as internal and external displays operate at same resolution (limited to 800x600 on current TFT LCD) and display rates
	Dynamic Display Configuration (DDC2 A and B) support for external SVGA monitor is provided.
External Display Drive	One SVGA/XGA-compatible analog output port
Display Size	User selected via Microsoft Windows
	Plug and Play support for DDC1 and DDC2 A and B
	Resolution (Pixels) Colors 640 x 480 256 640 x 480 64,000 640 x 480 16,800,000 800 x 600 256 800 x 600 64,000 800 x 600 16,800,000 1024 x 768 256 1280 x 1024 256 1600 x 1200 256
Internal Display	
Classification	Thin Film Transistor (TFT) 10.4 inch active-matrix color LCD display; CCFL backlight; intensity controllable via software
Resolution	800 x 600 pixels
Color Scale	262,144 colors (6-bit RGB)

Table 46: TLA714 front-panel interface

Characteristic	Description
QWERTY Keypad	ASCII keypad to support naming of files, traces, and keyboard equivalents of pointing device inputs for menus
HEX Keypad	HEX keypad supporting text entry functions
Special Function Knobs	Various functions
Integrated Pointing Device	GlidePoint touchpad
Dual USB Ports	Two USB (Universal Serial Bus) compliant ports
Mouse Port	PS/2 compatible mouse port utilizing a mini DIN connector
Keyboard Port	PS/2 compatible keyboard port utilizing a mini DIN connector

Table 47: TLA714 rear-panel interface

Characteristic	Description
Parallel Interface Port (LPT)	36-pin high-density connector supports standard Centronics mode, Enhanced Parallel Port (EPP), or Microsoft high-speed mode (ECP)
Serial Interface Port (COM A)	9-pin male sub-D connector to support RS-232 serial port
SVGA Output Port (SVGA OUT)	15-pin sub-D SVGA connector
Type I and II PC Card Port	Standard Type I and II PC-compatible PC card slot
Type I, II, and III PC Card Port	Standard Type I, II, and III PC-compatible PC card slot

Table 48: TLA714 AC power source

Characteristic	Description
Source Voltage and Frequency	90–250 V_{RMS}, 45–66 Hz, continuous range CAT II 100–132 V_{RMS}, 360–440 Hz, continuous range CAT II
Fuse Rating	
90 V - 250 V Operation (159-0046-00)	UL198/CSA C22.2 0.25 in × 1.25 in, Fast Blow, 8 A, 250 V
90 V - 250 V Operation (159-0381-00)	IEC 127/Sheet 1 5 mm × 20 mm, Fast Blow, 6.3 A, 250 V
Maximum Power Consumption	600 W line power maximum
Steady-State Input Current	6 A_{RMS} maximum
Inrush Surge Current	70 A maximum

Table 48: TLA714 AC power source (Cont.)

Characteristic	Description
Power Factor Correction	Yes
On/Standby Switch and Indicator	Front Panel On/Standby switch, with LED indicator located next to switch
	The power cord provides main power disconnect.

Table 49: TLA714 secondary power

Characteristic	Description			
✓ DC Voltage Regulation	Voltage	Minimum	Nominal	Maximum
(Combined System, voltage available at each slot)	+24 V	23.28 V	24.24 V	25.20 V
	+12 V	11.64 V	12.12 V	12.60 V
	+5 V	4.875 V	5.063 V	5.250 V
	-2 V	-2.10 V	-2.00 V	-1.90 V
	-5.2 V	-5.460 V	-5.252 V	-5.044 V
	-12 V	-12.60 V	-12.12 V	-11.64 V
	-24 V	-25.20 V	-24.24 V	-23.28 V

Table 50: TLA714 cooling

Characteristic	Description
Cooling System	Forced air circulation (negative pressurization) utilizing six fans operating in parallel
Cooling Clearance	2 in (51 mm), sides and rear; unit should be operated on a flat, unobstructed surface
Slot Activation	Installing a module activates the cooling for the corresponding occupied slots by opening the air flow shutter mechanism. Optimizes cooling efficiency by only applying airflow to modules that are installed.

Table 51: TLA714 mechanical

| Characteristic	Description
Overall Dimensions	(See Figure 4 for overall chassis dimensions.)
Height (with feet)	9.25 in (235 mm)
Width	17.0 in (432 mm)
Depth	17.5 in (445 mm)
Weight (Typical)	30 lbs 12 oz. (13.9 kg) with no modules installed, 2 dual-wide slot covers, and empty pouch
Shipping configuration (Typical)	88 lbs (26.3 kg) minimum configuration (no modules or probes), with all standard accessories
	87 lb (39.5 kg) full configuration, with 2 TLA7P4 modules and standard accessories (including probes)
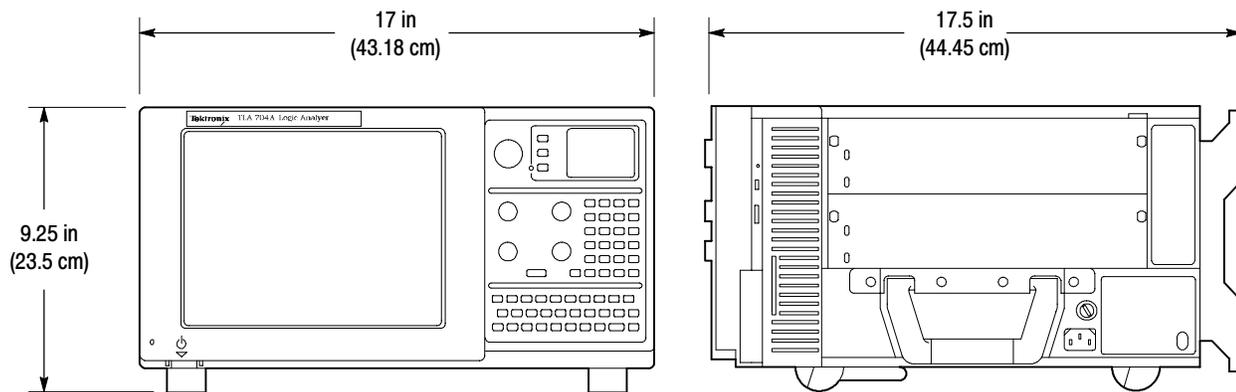
Figure 4: Dimensions of TLA714 portable mainframe

Benchtop and Expansion Mainframe Characteristics

Tables 52 through 56 list the specifications for the TLA720/721 Benchtop mainframe and the TLA7XM expansion mainframe.

Table 52: Benchtop and expansion mainframe AC power source

Characteristic	Description
Source Voltage	90–250 V$_{RMS}$, 45–66 Hz, continuous range CAT II 100–132 V$_{RMS}$, 360–440 Hz, continuous range CAT II
Maximum Power Consumption	1450 W line power (the maximum power consumed by a fully loaded 13-slot instrument)
Fuse Rating (Current and voltage ratings and type of fuse used to fuse the source line voltage)	
90 V – 132 VAC$_{RMS}$ Operation High-power/Low Line (159-0379-00)	Safety: UL198G/CSA C22.2 Size: 0.25 in × 1.25 in Style: Slow acting Rating: 20 A/250 V
103 V – 250 VAC$_{RMS}$ Operation (159-0256-00)	Safety: UL198G/CSA C22.2 Size: 0.25 in × 1.25 in Style: No. 59/Fast acting Rating: 15 A/250 V
207 V – 250 VAC$_{RMS}$ Operation (159-0381-00)	Safety: IEC 127/Sheet 1 Size: 5 mm × 20 mm Style: Fast acting "F", high-breaking capacity Rating: 6.3 A/250 V
Inrush Surge Current	70 A maximum
Steady State Input Current	16.5 A$_{RMS}$ maximum at 90 VAC$_{RMS}$ 6.3 A$_{RMS}$ maximum at 207 VAC$_{RMS}$
Power Factor Correction (Typical)	0.99 at 60 Hz operation and 0.95 at 400 Hz operation
ON/Standby Switch and Indicator	Front Panel On/Standby switch with integral power indicator

Table 53: Benchtop and expansion mainframe secondary power

Characteristic	Description			
↙ DC Voltage Regulation (Combined System, voltage available at each slot)	Voltage	Minimum	Nominal	Maximum
	+24 V	23.28 V	24.24 V	25.20 V
	+12 V	11.64 V	12.12 V	12.60 V
	+5 V	4.875 V	5.063 V	5.250 V
	-2 V	-2.10 V	-2.00 V	-1.90 V
	-5.2 V	-5.460 V	-5.252 V	-5.044 V
	-12 V	-12.60 V	-12.12 V	-11.64 V
	-24 V	-25.20 V	-24.24 V	-23.28 V

Table 54: Benchtop and expansion mainframe cooling

Characteristic	Description
Cooling system	Forced air circulation system (positive pressurization) using a single low-noise centripetal (squirrel cage) fan configuration with no filters for the power supply and 13 module slots.
Fan speed control	Rear panel switch selects between full speed and variable speed. Slot exhaust temperature and ambient air temperature are monitored such that a constant delta temperature is maintained.
Slot activation	Installing a module activates the cooling for the corresponding occupied slots by opening the air flow shutter mechanism. Optimizes cooling efficiency by only applying airflow to modules that are installed.
Pressurization	Positive pressurization system, all chambers including modules
Slot airflow direction	P2 to P1, bottom of module to top of module
Mainframe air intake	Lower fan-pack rear face and bottom
Mainframe air exhaust	Top-sides and top-rear back. Top rear-back exhaust redirected to the sides by the fan pack housing to minimize reentry into the intake.
Δ Temperature readout sensitivity	100 mV/ °C with 0 °C corresponding to 0 V output
Temperature sense range	-10 °C to +90 °C, delta temperature ≤ 50 °C
Clearance	2 in (51 mm), rear, top, and sides
Fan speed readout	RPM = 20 × (Tach frequency) or 10 ÷ (+Pulse Width) where (+Pulse Width) is the positive width of the TACH1 fan output signal measured in seconds
Fan speed range	650 to 2250 RPM

Table 55: Enhanced monitor

Characteristic	Description
Voltage readout	+24 V, –24 V, +12 V, –12 V, +5 V, –5.2 V, –2 V, +5 $V_{Standby}$ if present, and +5 $V_{External}$ via RS232
Voltage readout accuracy (Typical)	±3% maximum
Current readout	Readout of the present current on the +24 V, –24 V, +12 V, –12 V, +5 V, –2 V, –5.2 V rails via RS232
Current readout accuracy (Typical)	±5% of maximum power supply I_{mp}
Rear panel connector levels	±25 VDC maximum, 1 A maximum per pin
	(Provides access for RS-232 host to enhanced monitor)

Table 56: Benchtop and expansion mainframe mechanical

Characteristic	Description
Overall Dimensions	(See Figures 5 and 6 for overall dimensions.)
Standard	
Height (with feet)	13.7 in (346.7 mm) including feet
Width	16.7 in (424.2 mm)
Depth	26.5 in (673.1 mm)
Rackmount	
Height	13.25 in (336.6 mm)
Width	18.9 in (480.1 mm)
Depth	28.9 in to 33.9 in (734.1 mm to 861.1 mm) in 0.5 in increments, user selectable
Benchtop controller dimensions	
Height	10.32 in (262.1 mm)
Width	2.39 in (60.7 mm)
Depth	14.75 in (373.4 mm)
Expansion module dimensions	
Height	10.32 in (262.1 mm)
Width	1.25 in (31.75 mm)
Depth	14.75 in (373.4 mm)
Weight	
Mainframe with benchtop controller and slot fillers (Typical)	58 lbs 11 oz. (26.7 kg)

Table 56: Benchtop and expansion mainframe mechanical (Cont.)

| Characteristic	Description
Shipping configuration (Typical)	60 lbs 11 oz. (26.7 kg) minimum configuration with controller (only) and all standard accessories (two manuals, five dual-wide and one single-wide slot filler panels, power cord, empty pouch, front cover, keyboard, software, and cables)
	187 lbs (85 kg) fully configured, same as above with the addition of five LA modules (four TLA7P4 modules, one TLA7N4 module) and all module standard accessories (probes and clips)
Benchtop controller	6 lbs 10 oz. (3.0 kg)
Expansion module	3 lbs (1.4 kg)
Maximum per slot	5 lbs (2.27 kg)
Rackmount kit adder	20 lbs (9.1 kg)
Size	
Benchtop controller	Three slots wide
Expansion module	Single slot wide
Acoustic noise level (*Typical*)	
Variable fan speed (at 860 RPM)	43.2 dBA weighted (front) 43.8 dBA weighted (back)
Full speed fan (switched at rear)	66.2 dBA weighted (front) 66.2 dBA weighted (back)
Construction materials	Chassis parts, aluminum alloy Front panel and trim pieces, plastic Circuit boards, glass laminate
Finish type	Mainframes are Tektronix silver gray with dark gray trim on fan pack and bottom feet support rails. Benchtop controllers are Tektronix silver gray on front lexan and injector/ejector assemblies with a black FDD and PC card ejector buttons.

16.7 in
(42.4 cm)

26.5 in
(67 cm)

13.7 in
(35 cm)

13.3 in
(34 cm)
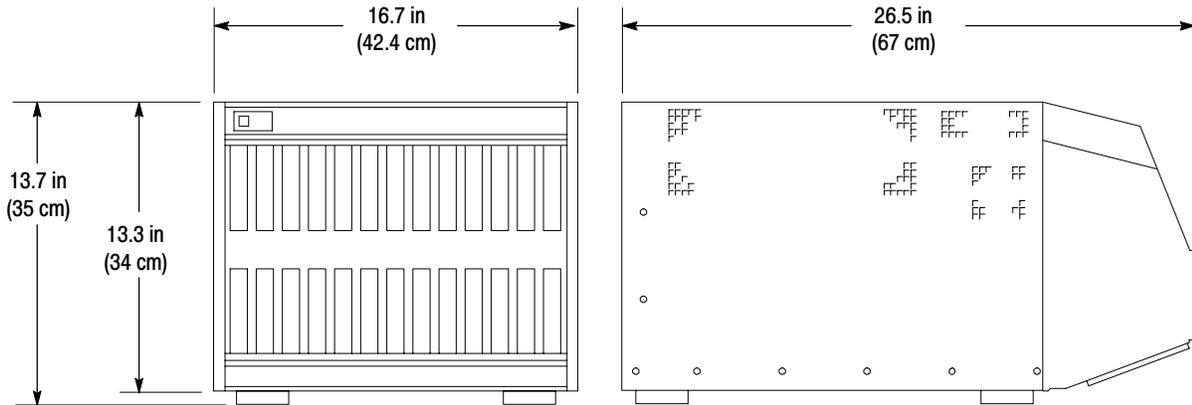
Figure 5: Dimensions of the benchtop and expansion mainframe

18.9 in
(48 cm)

28.9 in (73.4 cm) Min to
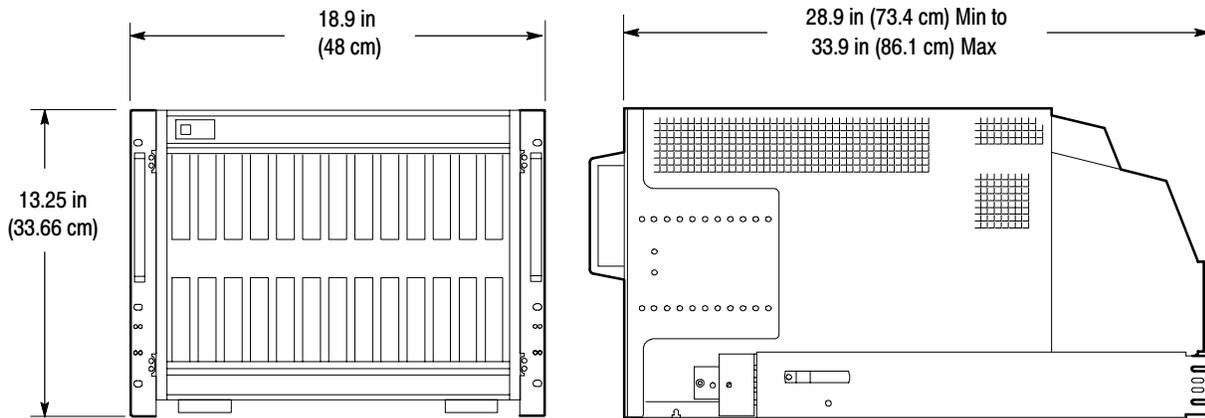33.9 in (86.1 cm) Max

13.25 in
(33.66 cm)

Figure 6: Dimensions of the benchtop and expansion mainframe with rackmount option

TLA721 Dual Monitor Benchtop Controller Characteristics

Tables 57 and 58 lists the specifications for the TLA721 Dual Monitor Benchtop Controller.

Table 57: TLA721 benchtop controller characteristics

Characteristic	Description
Operating system	Microsoft Windows 2000
Microprocessor	Intel 733 MHz Pentium III configuration with an Intel 815E chip-set
Main memory	Two 144 pin SODIMM sockets support one or two SDRAM modules.
Available configurations	16, 32, 64, 256 MB per SODIMM
Installed configuration	512 MB maximum configuration
Speed	133 MHz
CAS latency	2, 3
RAS to CAS delay	2, 3
RAS precharge	2, 3
DRAM cycle time	5/7 or 7/9
Cache memory	512 KB, level 2 (L2) write-back cache
Flash BIOS	512 KB
	Provides PC plug-and-play services with and without Microsoft Windows operating system.
	Flash based BIOS field upgradable via a floppy disk
	Forced recovery jumper is provided
Real-time clock and CMOS setups NVRAM	Real-time clock/calendar. Standard and advanced PC CMOS setups: see BIOS specifications
RTC, CMOS setup, & PnP NVRAM retention time (Typical)	Battery life is typically > 7 years
Floppy disk drive	Standard 3.5 inch, 1.44 MB, high-density, double-sided, PC-compatible high-density floppy disk drive
Transfer rate	500 Kbits per second
Access time (ave.)	194 ms
Bootable replaceable hard disk drive	Standard PC compatible IDE (Integrated device Electronics) hard disk drive residing on an EIDE interface
Size	40 GByte
	Continually subject to change due to the fast-moving PC component environment.
	These storage capacities valid at product introduction.
Interface	ATA-5/Enhanced IDE (EIDE)

Table 57: TLA721 benchtop controller characteristics (Cont.)

Characteristic	Description
Average seek time	Read 12 ms
I/O data-transfer rate	33.3 MB/s maximum (U-DMA mode 2)
Average latency	7/14 ms
Cache buffer	512 KB
CD-RW Drive	Standard PC compatible IDE (Integrated device Electronics) 8x-8x-24x CD-RW drive residing on an IDE interface. Continually subject to change due to the fast-moving PC component environment.
Applicable formats	CD-DA; CE-ROM Mode 1, Mode 2; CD-ROM XA Mode 2 (Form 1, Form 2); Photo CD (single/multi session); Enhanced CD
Interface	IDE (ATAPI)
Average access time	130 ms
Data-transfer rate (burst sustained)	16.7 MB per second maximum, 1290–3000 KB per second

Table 57: TLA721 benchtop controller characteristics (Cont.)

Characteristic	Description
Display classification	Standard PC graphics accelerator technology (bitBLT based) residing on the Peripheral Component Interconnect (PCI) bus capable of supporting external color VGA, SVGA, or XGA monitors
Display configuration	Hardware automatically senses a missing flat panel LCD in the benchtop mainframe and defaults to the external SVGA monitor output during the BIOS boot sequence (no internal TFT LCD display exists). This is indicated by a single beep during the boot sequence. Dynamic Display Configuration 1 (DDC1) support for the external monitor is provided.
Display memory	4 MB SDRAM is on board the video controller; no external video memory
Display drive Display size	Two VGA, SVGA, or XGA compatible analog output ports User selected via Microsoft Windows Plug and Play support for DDC1 and DDC2 A and B (Primary video port with Silicon Motion Chip) Resolution (Pixels) Colors Refresh Rates 640 x 480 256, 64 K, 16.8 M 60, 75, 85 800 x 600 256, 64 K, 16.8 M 60, 75, 85 1024 x768 256, 64 K, 16.8 M 60, 75, 85 1280 x 1024 256, 64 K, 16.8 M 60 1600 x 600 256, 64 K 60 1600 x 1200 256, 64 K 60 (Secondary video port with 815E Chip set) Resolution (Pixels) Colors Refresh Rates 640 x 480 256, 64 K, 16.8 M 60, 75, 85 800 x 600 256, 64 K, 16.8 M 60, 75, 85 1024 x768 256, 64 K, 16.8 M 60, 75, 85 1280 x 1024 256, 64 K, 16.8 M 60, 75, 85 1600 x 1200 256 60, 75

Table 58: Front panel characteristics

Characteristic	Description
SVGA output port (SVGA)	Two 15-pin sub-D SVGA connectors
Dual USB ports	Two USB (Universal Serial Bus) compliant ports
Mouse port	Front panel mounted PS2 compatible mouse port utilizing a mini DIN connector
Keyboard port	Front panel mounted PS2 compatible keyboard port utilizing a mini DIN connector

Table 58: Front panel characteristics (Cont.)

Characteristic	Description
Parallel interface port (LPT)	36-pin high-density connector supports standard Centronics mode, Enhanced Parallel Port (EPP), or Microsoft high-speed mode (ECP)
Serial interface port (COM)	9-pin male sub-D connector to support an RS232 serial port
PC CardBus32 port	Standard Type I and II PC compatible PC card slot
Type I, II, and III PC Card Port	Standard Type I, II, and III PC compatible PC card slot

TLA720 Benchtop Controller Characteristics

Tables 59 through 60 list the specifications for the TLA720 Benchtop Controller.

Table 59: TLA720 benchtop controller characteristics

Characteristic	Description
Operating System	Microsoft Windows
Microprocessor	Intel Pentium 266 MHz PC-AT configuration with an Intel chip-set
Main Memory	SDRAM
Style	Two 144 pin SODIMM sockets support one or two SDRAM modules.
Installed Configuration	128 MB Two 64 MB SDRAM modules installed
Speed	60 ns
Cache Memory	256 K, level 2 (L2) write-back cache
Flash BIOS	512 KB Provides PC plug-and-play services with and without Microsoft Windows operating system. Flash based BIOS field upgradable via a floppy disk
Real-Time Clock and CMOS Setups NVRAM (Typical)	Real-time clock/calendar, with typical 7-year life. Standard and advanced PC CMOS setups: see BIOS specification.
Floppy Disk Drive	Standard 3.5 inch, 1.44 MB, double-sided, PC-compatible high-density floppy disk drive
Bootable Replaceable Hard Disk Drive	Standard PC compatible IDE (Integrated device Electronics) hard disk drive residing on an EIDE interface
Size	Maximum 30 GByte Continually subject to change due to the fast-moving PC component environment. These storage capacities valid at product introduction.
Interface	ATA-4/Enhanced IDE (EIDE)
Average seek time	Read 13 ms
I/O data-transfer rate	33.3 MB/s maximum (U-DMA mode 2)
CD-RW Drive	Standard PC compatible IDE (Integrated device Electronics) 8x-8x-24x CD-RW drive residing on an IDE interface. Continually subject to change due to the fast-moving PC component environment.

Table 59: TLA720 benchtop controller characteristics (Cont.)

Characteristic	Description
Display Classification	Standard PC graphics accelerator technology (bitBLT based) capable of driving external color VGA, SVGA, or XGA monitors
Display Memory	DRAM based frame-buffer memory
Size	2 MB
Display Drive	One VGA, SVGA, or XGA compatible analog output port
Display Size	User selected via Microsoft Windows
	Plug and Play support for DDC1 and DDC2 A and B
	Resolution (Pixels) Colors 640 x 480 256 640 x 480 64,000 640 x 480 16,800,000 800 x 600 256 800 x 600 64,000 800 x 600 16,800,000 1024 x768 256 1280 x 1024 256 1600 x 1200 256
SVGA Output Port (SVGA)	The SVGA port utilizing a 15-pin sub-D SVGA connector
Dual USB Ports	Two USB (Universal Serial Bus) compliant ports
Mouse Port	Front panel mounted PS2 compatible mouse port utilizing a mini DIN connector
Keyboard Port	Front panel mounted PS2 compatible keyboard port utilizing a mini DIN connector
Parallel Interface Port (LPT)	36-pin high-density connector supports standard Centronics mode, Enhanced Parallel Port (EPP), or Microsoft high-speed mode (ECP)
Serial Interface Port (COM)	9-pin male sub-D connector to support an RS232 serial port
Type I and II PC Card Port	Standard Type I and II PC compatible PC card slot
Type I, II, and III PC Card Port	Standard Type I, II, and III PC compatible PC card slot

Table 60: TLA720 benchtop controller mechanical characteristics

Characteristic	Description
Weight (*Typical*)	6 lb. 10 oz. (2.9 kg)
Size	Three slots wide
Overall dimensions	
Height	10.32 in (262 mm)
Width	3.6 in (83 mm)
Depth	14.7 in (373 mm)

TLA7Axx/TLANAx Series Logic Analyzer Module Characteristics

Tables 61 though 69 list the specifications of the TLA7Axx/TLA7NAx Series Logic Analyzer modules.

Table 61: TLA7Axx/TLA7NAx input parameters (with probes)

Characteristic	Description
✓ Threshold accuracy (Certifiable parameter)	± (35 mV + 1% of the threshold voltage setting)
Threshold range and step size	Setable from +4.5 V to −2.0 V in 5 mV steps
Threshold channel selection	16 threshold groups assigned to channels. Each probe has four threshold settings, one for each of the clock/qualifier channels and one per group of 16 data channels.
✓ Channel to channel skew	≤ 400 ps maximum When merged, add the following for slave modules: 0.0 ns when data is acquired on the slave modules through local clocks 125 ps when data is acquired on the slave modules via the master modules'clock and merge deskew has been performed. 375 ps when data is acquired on the slave modules via the master module's clock and merge deskew has *NOT* been performed.
Channel to channel skew (Typical)	≤ 300 ps When merged, add the following for slave modules: 0.0 ns when data is acquired on the slave modules through local clocks 125 ps when data is acquired on the slave modules via the master modules'clock and merge deskew has been performed. 375 ps when data is acquired on the slave modules via the master module's clock and merge deskew has *NOT* been performed.
Sample uncertainty	
Asynchronous	Sample period
Synchronous	125 ps
Minimum slew rate (Typical)	0.2 V/ns
Input voltage range	−2.5 V to +5 V
Maximum operating voltage swing	6.0 V peak-to-peak
Probe overdrive	
Single ended probes	± 150 mV or ± 25% of signal swing minimum required beyond threshold, whichever one is greater
Differential probes	$V_{pos} - V_{neg}$ is ≥ $150 mV_{p-p}$
Maximum nondestructive input signal to probe	± 15 V
Minimum input pulse width (single channel) (Typical)	
P6860, P6880, P6960, and P6980 probes	500 ps
P6810 probes	750 ps

Table 61: TLA7Axx/TLA7NAx input parameters (with probes) (Cont.)

Characteristic	Description
Delay time from probe tip to input probe connector (*Typical*)	
P6860, P6960, and P6980 probes	7.7 ns $\pm$ 60 ps
P6810 and P6880 probes	7.7 ns $\pm$ 80 ps

Table 62: TLA7Axx analog output

Characteristic	Description
Number of outputs	Four analog outputs regardless of the module channel width. Any four of the module's channels can be mapped to the four analog outputs.
Attenuation	10X mode for normal operation 5X mode for small signals (–1.5 V to +2.5 V)
Bandwidth (Typical)	2 GHz
Accuracy (gain and offset) (Typical)	$\pm$ (50 mV + 2% of signal amplitude)

Table 63: Channel width and depth

Characteristic	Description
Number of channels	
TLA7AA4, TLA7AB4, TLA7NA4	128 data, 8 clock/qualifier
TLA7AA3, TLA7NA3	96 data, 6 clock/qualifier
TLA7AA2, TLA7AB2, TLA7NA2	64 data, 4 clock/qualifier
TLA7AA1, TLA7NA1	32 data, 2 clock/qualifier
Acquisition memory depth	
TLA7AAx, TLA7NAx series	32 M per channel, maximum
TLA7ABx series	64 M per channel, maximum

Table 64: Clocking

Characteristic	Description	
Asynchronous clocking		
✔ Internal sampling period	500 ps to 50 ms in a 1–2–5 sequence. Storage control can be used to only store data when it has changed (transitional storage)	
	2 ns minimum for all channels 1 ns minimum for half channels (using 2:1 Demultiplex mode) 0.5 ns minimum for quarter channels (using 4:1 Demultiplex mode)	
✔ Minimum recognizable word[1] (across all channels)	Channel-to-channel skew + sample uncertainty	
	Example for a P6860 high-density probe and a 2 ns sample period: 400 ps + 2 ns = 2.4 ns	
Synchronous clocking		
Master clock channels[2]	Product	Clock channels
	32+2 module	2
	64+4 module	4
	96+6 module	4
	128+8 module	4
Merged slave clock channels[2] (64+4 channel modules and 32+2 channel modules cannot be merged.)	Product	Clock channels
	96+6 module	4
	128+8 module	4
Qualifier channels[3]	Product	Qualifier channels
	32+2 module	0
	64+4 module	0
	96+6 module	2
	128+8 module	4
Single channel setup and hold window size (Typical)	500 ps	
✔ Single module setup and hold window size (data and qualifiers)	Maximum window size = Maximum channel-to-channel skew + (2 x sample uncertainty) + 100 ps Maximum setup time = User interface setup time + 75 ps Maximum hold time = User interface hold time + 50 ps	
	Example using P6810, P6860, or P6880 probe and user interface setup and hold of 625/0 typical: Maximum window size = 400 ps + 250 ps + 100 ps = 750 ps Maximum setup time = 625 ps + 75 ps = 700 ps Maximum hold time = 0.0 ps + 50 ps = 50 ps	
Single module setup and hold window size (data and qualifiers) (Typical)	Typical window size = Typical channel-to-channel skew + (2 x sample uncertainty) + 75 ps	
	Example using P6860 probe: 300 ps + 250 ps + 75 ps = 625 ps	

Table 64: Clocking (Cont.)

Characteristic	Description
Merged module setup and hold window size (data and qualifiers) (Typical)	Maximum window size = Single module setup and hold + merge skew
	When determining the required setup and hold window for merged modules, take into consideration if the slave module's local clocks are used to acquire data and if a merge deskew has been performed. If the slave module uses its own clocks to acquire data, then the typical and maximum setup and hold values are the same as a stand-alone module (the same is true for the master module itself). The only time the additional merge skew values apply is when the clocks on the master module acquire data on the slave modules.
	When a slave module acquires data using its own local clocks, merge skew = 0 ps
	When a slave module acquires data using clocks from the master module *without* merge deskew, merge skew = 375 ps
	When a slave module acquires data using clocks from the master module and *has* had merge deskew performed, merge skew = 125 ps.
	Example using P6810, P6860, or P6880 probe with slave module acquiring data via clocks from the master module *without* merge deskew:
	Maximum window size = 750 ps + 375 ps = 1.125 ns
	Typical window size = 625 ps + 375 ps = 1.000 ns
	The user interface setup and hold window for merge applications is affected as follows by merge skew:
	Typical setup time = User interface setup time + (merge skew/2)
	Typical hold time = User interface hold time + (merge skew/2)
	Maximum setup time = User interface setup time + 75 ps + (merge skew/2)
	Maximum hold time = User interface hold time + 50 ps + (merge skew/2)
	Example using P6810, P6860, or P6880 probe, with user interface default setup and hold time of 625/0 typical, and merge configuration that *has* had merge deskew performed:
	Typical setup time = 625 ps + (125 ps/2) = 688 ps
	Typical hold time = 0 ps + (125 ps/2) = 62 ps
	Maximum setup time = 625 ps + 75 ps + (125 ps/2) = 763 ps
	Maximum hold time = 0 ps + 50 ps + (125 ps/2) = 112 ps
Setup and hold window range	For each channel, the setup and hold window can be moved from +8.0 ns (T_s typical) to -8.0 ns (T_s typical) in 0.125 ns steps (setup time).
	The setup and hold window can be shifted toward the setup region by 0 ns, 4 ns, or 8 ns. With a 0 ns shift, the range is +8 ns to -8 ns; with a 4 ns shift, the range is +12 ns to -4 ns; with an 8 ns shift, the range is +16 ns to 0 ns. The sample point selection region is the same setup and hold window. Setup times are specified as typical figures. Hold time follows the setup time by the setup and hold window size.
✓ Maximum synchronous clock rate TLA7Axx series	450 MHz in full-speed mode (2.2 ns minimum between active clock edges)
	235 MHz in half-speed mode (4.25 ns minimum between active clock edges)
	120 MHz in quarter-speed mode (8.3 ns minimum between active clock edges)
	800 MHz on half channels[4]
	Software controls the selection between full-speed and half-speed modes.

Table 64: Clocking (Cont.)

Characteristic	Description
✔ Maximum synchronous clock rate TLA7NAx series	450 MHz in full-speed mode (2.2 ns minimum between active clock edges)
	235 MHz in full-speed mode (4.25 ns minimum between active clock edges)
	Software controls the selection between full-speed and half-speed modes.
Demultiplex clocking (two clock edges required)	
Demultiplex channels (2:1) TLA7AA3, TLA7AA4, TLA7AB4, TLA7NA3, TLA7NA4 modules	Any individual channel can be demultiplexed with its partner channel. If multiplexing is enabled, all of the A and D channels are multiplexed; there is no individual selection. Channels demultiplex as follows: A3(7:0) to/from D3(7:0) A2(7:0) to/from D2(7:0) A1(7:0) to/from D1(7:0) A0(7:0) to/from D0(7:0) E3(7:0) to/from E1(7:0) TLA7AA4, TLA7AB4, and TLA7NA4 only E2(7:0) to/from E0(7:0) TLA7AA4, TLA7AB4, and TLA7NA4 only CK3 to/from Q2 TLA7AA4, TLA7AB4, and TLA7NA4 only CK2 to/from Q3 TLA7AA4, TLA7AB4, and TLA7NA4 only CK2 to/from Q3 CK2 to/from Q3
TLA7AA1, TLA7AA2, TLA7AB2, TLA7NA1, TLA7NA2 modules	Any individual channel can be demultiplexed with its partner channel. If multiplexing is enabled, all of the A and D channels are multiplexed; there is no individual selection. Channels demultiplex as follows: A3(7:0) to/from C3(7:0) A2(7:0) to/from C2(7:0) A1(7:0) to/from D1(7:0) TLA7AA2, TLA7NA2, TLA7NA2 modules only A0(7:0) to/from D0(7:0) TLA7AA2, TLA7NA2, TLA7NA2 modules only
Demultiplex channels (4:1) TLA7AA3, TLA7AA4, TLA7AB4, TLA7NA3, TLA7NA4 modules	Unlike the 2:1 Demultiplex, the channels within a group of four cannot arbitrarily drive the others. E3(7:0) to E2(7:0), E1(7:0), E0(7:0) TLA7AA4, TLA7AB4 modules only A3(7:0) to A2(7:0), D3(7:0), D2(7:0) A1(7:0) to A0(7:0), D1(7:0), D0(7:0) C3(7:0) to C2(7:0), C1(7:0), C0(7:0) CK3 to CK2, Q3, Q2 TLA7AA4, TLA7AB4, modules only CK1 to CK0, Q1, Q0
TLA7AA1, TLA7AA2, TLA7AB2, modules	Unlike the 2:1 Demultiplex, the channels within a group of four cannot arbitrarily drive the others. A1(7:0) to A0(7:0), D1(7:0), D0(7:0) TLA7AA2, TLA7AB2, only C3(7:0) to C2(7:0), A3(7:0), A2(7:0)

Table 64: Clocking (Cont.)

Characteristic	Description
Time between Demultiplex clock edges (Typical)	Same limitations as normal synchronous acquisition
Source synchronous clocking (TLA7Axx)	
Clocks per module	Four
Clocks with merged modules	When merged, the slave modules have two clocks available from the master module. Including the local clocks, the total is six clocks.
Clock groups	Four for a single module and for a merged system
Size of clock group valid FIFO	Four stages when operated at 235 MHz or below (three stages when operated above 235 MHz); this allows four (source synchronous or other) clocks to occur before the clock that completes the Clock Group Valid signal for that group.
Source synchronous clock alignment window	Channel-to-channel skew only
Source synchronous clock reset	The Clock Group Valid FIFO can be reset in one of the two ways:
	1. By the overflow of a presettable (0–255) 8-bit counter that counts one of the following clocks: 2 ns Clock or the master heartbeat clock (synchronous or asynchronous). An active edge places the reset count to its preset value. An active clock edge will clear the Clock Group Valid reset before the clock gets to the FIFO so that no data is lost.
	2. By enabling an external reset. In this mode, one of the clock channels must be traded on the master module to act as a level-sensitive reset input. Any one of the clocks can be selected. A polarity selection is available. This mode affects all Clock Group Complete circuits.
	Neither one of the above modes can be intermixed; one or the other must be selected.
Clocking state machine	
Pipeline delays	Channel groups can be programmed with a pipeline delay of 0 through 7 active clock changes.

[1] Specification only applies with asynchronous (internal) clocking. With synchronous clocking, the setup and hold window size applies.

[2] Any or all clock channels can be enabled. For an enabled clock channel, either the rising, falling, or both edges can be selected as active clock edges. Clock channels are stored.

[3] Qualifier channels are stored.

[4] This is a special mode and has some limitations such as the clocking state machine and trigger state machine only running at 500 MHz.

Table 65: TLA7Axx/TLA7NAx module trigger system

Characteristic	Description
Trigger resources	
Word recognizers and range recognizers	16, word recognizers can be combined to form full width, double bounded range recognizers. The following selections are available:
	16 word recognizers 0 range recognizers 13 word recognizers 1 range recognizer 10 word recognizers 2 range recognizers 7 word recognizers 3 range recognizers 4 word recognizers 4 range recognizers
Range recognizer channel order	From most-significant probe group to least-significant probe group:
	C3 C2 C1 C0 E3 E2 E1 E0 A3 A2 D3 D2 A1 A0 D1 D0 Q3 Q2 Q1 Q0 CK3 CK2 CK1 CK0
	Missing channels for modules with fewer than 136 channels are omitted. When merged, the range recognition extends across the modules. The master module contains the most-significant groups.
Glitch detector (normal asynchronous clock mode)	Channel groups can be enabled to detect glitches.
	Glitches are subject to pulse width variations of up to $\pm$ 125 ps
Minimum detectable glitch pulse width (Typical)	Minimum input pulse width (single channel) P6860, P6960 high density probe: 500 ps P6880, P6980 differential probe: 500 ps P6810 general purpose probe: 750 ps
Setup and hold violation detector (normal synchronous clock mode)	Any channel can be enabled to detect a setup or hold violation. The range is from 8.0 ns before the clock edge to 8.0 ns after the clock edge in 0.125 ns steps. The channel setup and hold violation size can be individually programmed.
	The range can be shifted towards the positive region by 0 ns, 4 ns, or 8 ns. With a 0 ns shift, the range is +8 ns to -8 ns; with a 4 ns shift, the range is +12 ns to -4 ns; with an 8 ns shift, the range is +16 ns to 0 ns. The sample point selection region is the same as the setup and hold window.
	Any setup value is subject to variation of up to the channel skew specification. Any hold value is subject to variation of up to the channel skew specification.
Transition detector	16 transition detectors.
	Any channel group can be enabled or disabled to detect a rising transition, a falling transition, or both rising and falling transitions between the current valid data sample and the previous valid data sample.
Counter/timers	2 counter/timers, 51 bits wide, can be clocked up to 500 MHz Maximum count is 2^50-1 (excluding sign bit) Maximum time is 4.5×10^6 seconds or 52 days
	Counters can be used as setable, resettable, and testable flags. Counters can be reset, do nothing, increased, or decreased. Timers can be reset, started, stopped, or not changed. Counters and timers have zero reset latency and one clock terminal count latency.

Table 65: TLA7Axx/TLA7NAx module trigger system (Cont.)

Characteristic	Description
Signal In 1	A backplane input signal.
Signal In 2	A backplane input signal.
Trigger In	A backplane input signal that causes the main acquisition and the MagniVu acquisition to trigger if they are not already triggered.
Active trigger resources	16 maximum (excluding counter/timers) Word recognizers are traded off one-for-one as Signal In 1, Signal In 2, glitch detection, setup and hold detection, or transition detection resources are added.
Trigger states	16
✔ Trigger state sequence rate	Same rate as valid data samples received. 500 MHz maximum.
Trigger machine actions	
Main acquisition trigger	Triggers the main acquisition memory
Main trigger position	Programmable to any data sample (2 ns boundaries)
MagniVu trigger	Main acquisition machine controls the triggering of the MagniVu memory
MagniVu trigger position	Programmable within 2 ns boundaries and separate from the main acquisition memory trigger position
Increment/decrement counter	Counter/timers used as counters can be increased or decreased.
Start/stop timer	Either of the two counter/timers used as timers can be started or stopped.
Reset counter/timer	Either of the two counter/timers can be reset. When a counter/timer used as a timer is reset, the timer continues in the started or stopped state that it was prior to the reset.
Reloadable word recognizer (snapshot)	Loads the current acquired data sample into the reference value of the word recognizer via a trigger machine action. All data channels are loaded into their respective word recognizer reference register on a one-to-one manner.
Reloadable word recognizer latency	378 ns
Signal Out	A signal sent to the backplane to be used by other modules
Trigger Out	A signal sent to the backplane to trigger other modules
Storage control	
Storage	Storage is allowed only if a specific condition is met. The condition can use any of the trigger resources except for counter/timers. Storage commands defined in the current trigger state will override the global storage control. Storage can be used to start the acquisition with storage initially turned on (default setting) or off.
By event	Storage can be turned on or off; only the current sample can be stored. Event storage control overrides any global storage commands.

Table 65: TLA7Axx/TLA7NAx module trigger system (Cont.)

Characteristic	Description
Block storage (store stretch)	When enabled, 31 samples are stored before and after the valid sample.
	This allows the storage of a group of samples around a valid data sample when storage control is being used. This only has meaning when storage control is used. Block storage is disallowed when glitch storage or setup and hold violation storage is enabled.
Glitch violation storage	Glitch violation information can be stored to acquisition memory with each data sample when asynchronous clocking is used. The acquisition data storage size is reduced by half when this mode is enabled (the other half holds violation information). The fastest asynchronous clock rate is reduced to 4 ns.
Setup and hold violation storage	Setup and hold violation information can be stored to acquisition memory with each data sample when synchronous clocking is used. The acquisition data storage size is reduced by half when this mode is enabled (the other half holds violation information). The maximum synchronous clock rate in this mode is 235 MHz.

Table 66: MagniVu acquisition

Characteristic	Description
MagniVu sampling period	Data is asynchronously sampled and stored every 125 ps in a separate MagniVu (high-resolution) memory. The storage speed can be changed by software to 250 ps, 500 ps, or 1000 ps with no loss in memory depth so that the high resolution memory covers more time at a lower resolution.
MagniVu memory depth	Approximately 16 K per channel. The MagniVu memory is separate from the main acquisition memory.

Table 67: Merged modules

Characteristic	Description
Number of merged modules	2, 3, 4, or 5 adjacent modules can be merged. Only 102-channel modules or 136-channel modules can be merged. Merged modules can have unequal channel widths and channel depths.
Number of channels after merging	The sum of all channels available on each of the merged modules including clocks and qualifiers. No channels are lost when modules are merged.
Merged system acquisition depth	Channel depth is equal to that of the shallowest module.
Number of clock and qualifier channels after merging	The qualifier channels on the slave modules can only be used as data channels. They cannot influence the actual clocking function of the logic analyzer (for example, log strobe generation).
	The clock channels on the slave TLA7Axx modules can capture data on those modules for source-synchronous applications. Each slave module contributes four additional clock channels to the merged set. All clock and qualifier channels are stored to acquisition memory.

Table 67: Merged modules (Cont.)

Characteristic	Description
Merged system trigger resources	The same as a single module except for word recognizer width, setup and hold violation detector width, glitch detector width, and transition detector width has increased to equal that of the merged channel width. Range recognizers will increase to the merged channel width up to three modules; range recognition is not supported on the two outside slave modules.
Merged range significance	Most significant Master, Slave 1, Slave 2

Table 68: Data handling

Characteristic	Description
Nonvolatile memory retention time (*Typical*)	The battery life is integral to the NVRAM; battery life is > 10 years.

Table 69: Mechanical

Characteristic	Description
Material	Chassis parts are constructed of aluminum alloy. The front panel is constructed of plastic laminated to steel front panel. Circuit boards are constructed of glass laminate.
Weight	
136-channel module	5 lb 6 oz. (2.438 kg)
102-channel module	5 lb 4 oz. (2.381 kg)
68-channel module	5 lb 0.5 oz. (2.282 kg)
34-channel module	4 lb 15.5 oz. (2.254 kg)
Shipping weight	7 lb 12 oz. (3.515 kg) for 136-channel module when packaged for domestic shipment
Overall dimensions	
Height	10.32 in (262 mm)
Width	2.39 in (61 mm) with merge connector in the recessed position
	Width increases by 0.41 in (10.41 mm) with merge connector in the extended position
Length	14.7 in (373 mm)
Mainframe interlock	1.4 ECL keying is implemented

TLA7Lx/Mx/Nx/Px/Qx Module Characteristics

Tables 70 through 76 list the specifications of the TLALx/Mx/Nx/Px/Qx logic analyzer modules.

Table 70: LA module channel width and depth

Characteristic	Description	
Number of channels	Product	Channels
	TLA7N1, TLA7L1, TLA7M1	32 data and 2 clock
	TLA7N2, TLA7P2, TLA7Q2, TLA7L2, TLA7M2	64 data and 4 clock
	TLA7N3, TLA7L3, TLA7M3	96 data, 4 clock, and 2 qualifier
	TLA7N4, TLA7P4, TLA7Q4, TLA7L4, TLA7M4	128 data, 4 clock, and 4 qualifier
Acquisition memory depth	Product	Memory depth
	TLA7L1, TLA7L2, TLA7L3, TLA7L4	32 K or 128 K samples[1]
	TLA7M1, TLA7M2, TLA7M3, TLA7M4	512 K samples
	TLA7N1, TLA7N2, TLA7N3, TLA7N4	64 K or 256 K or 1 M or 4 M samples[1]
	TLA7P2, TLA7P4	16 M samples
	TLA7Q2, TLAQP4	64 M samples

[1] **PowerFlex options**

Table 71: LA module clocking

Characteristic	Description	
Asynchronous clocking		
✓ Internal sampling period[1]	4 ns to 50 ms in a 1-2-5 sequence 2 ns in 2x Clocking mode	
✓ Minimum recognizable word[2] (across all channels)	Channel-to-channel skew + sample uncertainty Example: for a P6417 or a P6418 Probe and a 4 ns sample period = 1.6 ns + 4 ns = 5.6 ns	
Synchronous clocking		
Number of clock channels[3]	Product	Clock channels
	TLA7N1, TLA7L1, TLA7M1	2
	TLA7N2, TLA7P2, TLA7Q2, TLA7L2, TLA7M2	4
	TLA7N3, TLA7L3, TLA7M3	4
	TLA7N4, TLA7P4, TLA7Q4, TLA7L4, TLA7M4	4

Table 71: LA module clocking (Cont.)

Characteristic	Description	
Number of qualifier channels	Product	Qualifier channels
	TLA7N1, TLA7L1, TLA7M1	0
	TLA7N2, TLA7P2, TLA7Q2, TLA7L2, TLA7M2	0
	TLA7N3, TLA7L3, TLA7M3	2
	TLA7N4, TLA7P4, TLA7Q4, TLA7L4, TLA7M4	4
✔ Setup and hold window size (data and qualifiers)	Maximum window size = Maximum channel-to-channel skew + (2 x sample uncertainty) + 0.4 ns Maximum setup time = User interface setup time + 0.8 ns Maximum hold time = User interface hold time + 0.2 ns Maximum setup time for slave module of merged pair = User Interface setup time + 0.8 ns Maximum hold time for slave module of merged pair = User Interface hold time + 0.7 ns Examples: for a P6417, P6418, or P6434 probe and user interface setup and hold of 2.0/0.0 typical: Maximum window size = 1.6 ns + (2 x 500 ps) + 0.4ns = 3.0 ns Maximum setup time = 2.0 ns + 0.8 ns = 2.8 ns Maximum hold time = 0.0 ns + 0.2 ns = 0.2ns	
Setup and hold window size (data and qualifiers) (Typical)	Channel-to-channel skew (*typical*) + (2 x sample uncertainty) Example: for P6417 or P6418 Probe = 1 ns + (2 x 500 ps) = 2 ns	
Setup and hold window range	For the TLA7Nx/Px/Qx logic analyzer modules, each channel of the setup and hold window can be moved from +8.5 ns (Ts) to –7.0 ns (Ts) in 0.5 ns steps (setup time). Hold time follows the setup time by the setup and hold window size. For the TLA7Lx and TLAMx logic analyzer modules, the user interface restricts the setup and hold window range to groups rather than individual channels.	
✔ Maximum synchronous clock rate[4]	200 MHz in full speed mode (5 ns minimum between active clock edges) 100 MHz in half speed mode (10 ns minimum between active clock edges)	
Demux clocking		
Demux Channels TLA7N3, TLA7N4, TLA7P4, TLA7Q4, TLA 7L3, TLA 7L4, TLA 7M3, TLA 7M4	Channels multiplex as follows: A3(7:0) to D3(7:0) A2(7:0) to D2(7:0) A1(7:0) to D1(7:0) A0(7:0) to D0(7:0)	
TLA7N1, TLA7N2, TLA7P2, TLA7Q2, TLA 7L1, TLA 7L2, TLA 7M1, TLA 7M2	Channels multiplex as follows: A3(7:0) to C3(7:0) A2(7:0) to C2(7:0) A1(7:0) to D1(7:0) TLA7N2, TLA7P2, TLA7Q2, TLA 7L2, TLA 7M2 only A0(7:0) to D0(7:0) TLA7N2, TLA7P2, TLA7Q2, TLA 7L2, TLA 7M2 only	
Time between DeMux clock edges[4] (Typical)	5 ns minimum between DeMux clock edges in full-speed mode 10 ns minimum between DeMux clock edges in half-speed mode	

Table 71: LA module clocking (Cont.)

Characteristic	Description
Time between DeMux store clock edges[4] (Typical)	10 ns minimum between DeMux master clock edges in full-speed mode 20 ns minimum between DeMux master clock edges in half-speed mode
Data Rate (Typical) TLA7N1, TLA7N2, TLA7P2, TLA7Q2, TLA7N3, TLA7N4, TLA7P4, TLA7Q4,	400 MHz (200 MHz option required) half channel. (Requires channels to be multiplexed.) These multiplexed channels double the memory depth.
Clocking state machine	
Pipeline delays	For the TLA7Nx/Px/Qx logic analyzer modules, each channel can be programmed with a pipeline delay of 0 through 3 active clock edges. For the TLA7Lx and TLAMx logic analyzer modules, the user interface restricts the programming to groups rather than individual channels.

[1] **It is possible to use storage control and only store data when it has changed (transitional storage).**

[2] **Applies to asynchronous clocking only. Setup and hold window specification applies to synchronous clocking only.**

[3] **Any or all of the clock channels may be enabled. For an enabled clock channel, the rising edge, falling edge, or both edges can be selected as the active clock edges. The clock channels are stored.**

[4] **Full and half speed modes are controlled by PowerFlex options and upgrade kits.**

Table 72: LA module trigger system

Characteristic	Description
Triggering Resources	
Word/Range recognizers	16 word recognizers. The word recognizers can be combined to form full width, double bounded, range recognizers. The following selections are available: 16 word recognizers 0 range recognizers 13 word recognizers 1 range recognizer 10 word recognizers 2 range recognizers 7 word recognizers 3 range recognizers 4 word recognizers 4 range recognizers
Range recognizer channel order	From most-significant probe group to least-significant probe group: C3 C2 C1 C0 E3 E2 E1 E0 A3 A2 D3 D2 A1 A0 D1 D0 Q3 Q2 Q1 Q0 CK3 CK2 CK1 CK0 Missing channels for modules with fewer than 136 channels are omitted. When merged, the range recognition extends across all the modules; the master module contains the most-significant groups. The master module is to the left (lower–numbered slot) of a merged pair. The master module is in the center when three modules are merged. Slave module 1 is located to the right of the master module, and slave module 2 is located to the left of the master module.
Glitch detector[1,2]	Each channel group can be enabled to detect a glitch

Table 72: LA module trigger system (Cont.)

Characteristic	Description
Minimum detectable glitch pulse width (Typical)	2.0 ns (single channel with a P6417, P6418, or P6434 probe)
Setup and hold violation detector[1,3]	Each channel can be enabled to detect a setup and hold violation. The range is from 8 ns before the clock edge to 8 ns after the clock edge. The range can be selected in 0.5 ns increments.

For the TLA7Lx and TLAMx logic analyzer modules, the user interface restricts the setup and hold violation detector to groups rather than individual channels.

The setup and hold violation of each window can be individually programmed. |
| Transition detector[1, 4] | Each channel group can be enabled or disabled to detect a transition between the current valid data sample and the previous valid data sample. |
| Counter/Timers | 2 counter/timers, 51 bits wide, can be clocked up to 250 MHz.
Maximum count is 2^{51}.
Maximum time is 9.007×10^6 seconds or 104 days.

Counters and timers can be set, reset, or tested and have zero reset latency. |
Signal In 1	A backplane input signal
Signal In 2	A backplane input signal
Trigger In	A backplane input signal that causes the main acquisition and the MagniVu™ acquisition to trigger if they are not already triggered
Active trigger resources	16 maximum (excluding counter/timers)

Word recognizers are traded off one-by-one as Signal In 1, Signal In 2, glitch detection, setup and hold detection, or transition detection resources are added. |
Trigger States	16
✓ Trigger State sequence rate	Same rate as valid data samples received, 250 MHz maximum
Trigger Machine Actions	
Main acquisition trigger	Triggers the main acquisition memory
Main trigger position	Trigger position is programmable to any data sample (4 ns boundaries)
Increment counter	Either of the two counter/timers used as counters can be increased.
Start/Stop timer	Either of the two counter/timers used as timers can be started or stopped.
Reset counter/timer	Either of the two counter/timers can be reset.

When a counter/timer is used as a timer and is reset, the timer continues in the started or stopped state that it was in prior to the reset. |
| Signal out | A signal sent to the backplane to be used by other modules |
| Trigger out | A trigger out signal sent to the backplane to trigger other modules |

Table 72: LA module trigger system (Cont.)

Characteristic	Description
Storage Control	
Global storage	Storage is allowed only when a specific condition is met. This condition can use any of the trigger machine resources except for the counter/timers. Storage commands defined in the current trigger state will override the global storage control. Global storage can be used to start the acquisition with storage initially turned on (default) or turned off.
By event	Storage can be turned on or off; only the current sample can be stored. The event storage control overrides any global storage commands.
Block storage	When enabled, 31 samples are stored before and after the valid sample. Block storage is disallowed when glitch storage or setup and hold violation is enabled.
Glitch violation storage	The acquisition memory can be enabled to store glitch violation information with each data sample when asynchronous clocking is used. The probe data storage size is reduced by one half (the other half holds the violation information). The fastest asynchronous clocking rate is reduced to 10 ns.

[1] **Each use of a glitch detector, setup and hold violation detector, or transition detector requires a trade-off of one word recognizer resource.**

[2] **Any glitch is subject to pulse width variation of up to the channel-to-channel skew specification + 0.5 ns.**

[3] **For TLA7N1, TLA7N2, TLA7N3, TLA7N4, TLA7P2, TLA7P4, TLA7Q2, and TLA7Q4 Logic Analyzer modules, any setup value is subject to variation of up to 1.8 ns; any hold value is subject to variation of up to 1.2 ns. For TLA7L1, TLA7L2, TLA7L3, TLA7L4, TLA7M1, TLA7M2, TLA7M3, and TLA7M4 Logic Analyzer modules, any setup value is subject to variation of up to 1.6 ns; any hold value is subject to variation of up to 1.4 ns.**

[4] **This mode can be used to create transitional storage selections where all channels are enabled.**

Table 73: LA module MagniVu™ feature

Characteristic	Description
MagniVu™ memory depth	2016 samples per channel
MagniVu™ sampling period	Data is asynchronously sampled and stored every 500 ps in a separate high resolution memory.

Table 74: LA module data handling

Characteristic	Description
Nonvolatile memory retention time (Typical)	Battery is integral to the NVRAM. Battery life is > 10 years.

Table 75: LA module input parameters with probes

Characteristic	Description
✓ Threshold Accuracy	±100 mV
Threshold range and step size	Settable from +5 V to –2 V in 50 mV steps
Threshold channel selection	16 threshold groups assigned to channels. P6417 and P6418 probes have two threshold settings, one for the clock/qualifier channel and one for the data channels. P6434 probes have four threshold settings, one for each of the clock/qualifier channels and two for the data channels (one per 16 data channels).
✓ Channel-to-channel skew	≤ 1.6 ns maximum (When merged, add 0.5 ns for the slave module.)
Channel-to-channel skew (Typical)	≤ 1.0 ns typical (When merged, add 0.3 ns for the slave module.)
Sample uncertainty	
Asynchronous:	Sample period
Synchronous:	500 ps
Probe input resistance (Typical)	20 kΩ
Probe input capacitance: P6417, P6434 (Typical)	2 pF
Probe input capacitance: P6418 (Typical)	1.4 pF data channels 2 pF CLK/Qual channels
Minimum slew rate (Typical)	0.2 V/ns
Maximum operating signal	6.5 V_{p-p} -3.5 V absolute input voltage minimum 6.5 V absolute input voltage maximum

Probe overdrive:
    P6417, P6418
 	
    P6434
	±250 mV or ±25% of signal swing minimum required beyond threshold, whichever is greater
	±300 mV or ±25% of signal swing minimum required beyond threshold, whichever is greater
	±4 V maximum beyond threshold

Maximum nondestructive input signal to probe	±15 V
Minimum input pulse width signal (single channel) (Typical)	2 ns
Delay time from probe tip to input probe connector (Typical)	7.33 ns

Table 76: LA module mechanical

Characteristic	Description
Slot width	Requires 2 mainframe slots
Weight (Typical)	5 lbs 10 oz. (2.55 kg) for TLA7N4 and TLA7P4 8 lbs (3.63 kg) for TLA7N4 and TLA7P4 packaged for domestic shipping
Overall dimensions	
Height	262 mm (10.32 in)
Width	61 mm (2.39 in)
Depth	373 mm (14.7 in)
Probe cables	
P6417 length	1.8 m (6 ft)
P6418 length	1.93 m (6 ft 4 in)
P6434 length	1.6 m (5 ft 2 in)
Mainframe interlock	1.4 ECL keying is implemented

DSO Module Characteristics

Tables 77 through 81 list the specifications for the DSO Module.

Table 77: DSO module signal acquisition system

Characteristic	Description		
✓ Accuracy, DC gain	±1.5% for full scale ranges from 20 mV to 100 V		
	±2.0% for full scale ranges <19.9 mV		
✓ Accuracy, internal offset[1]	*Full scale range setting*	*Offset accuracy*	
	10 mV – 1 V	±[(0.2% × | offset |) + 1.5 mV + (6% × full scale range)]	
	1.01 V – 10 V	±[(0.25% × | offset |) + 15 mV + (6% × full scale range)]	
	10.1 V – 100 V	±[(0.25% × | offset |) + 150 mV + (6% × full scale range)]	
✓ Analog bandwidth, DC–50 Ω coupled	*Full scale range setting*	*Bandwidth[2]*	
	10.1 V – 100 V	DC – 500 MHz (TLA7E1 and TLA7E2) DC – 500 MHz (TLA7D1 and TLA7D2)	
	100 mV – 10 V	DC – 1 GHz (TLA7E1 and TLA7E2) DC – 500 MHz (TLA7D1 and TLA7D2)	
	50 mV – 99.5 mV	DC – 750 MHz (TLA7E1 and TLA7E2) DC – 500 MHz (TLA7D1 and TLA7D2)	
	20 mV – 49.8 mV	DC – 600 MHz (TLA7E1 and TLA7E2) DC – 500 MHz (TLA7D1 and TLA7D2)	
	10 mV – 19.9 mV	DC – 500 MHz (TLA7E1 and TLA7E2) DC – 500 MHz (TLA7D1 and TLA7D2)	
Bandwidth, analog, selections	20 MHz, 250 MHz, and FULL on each channel		
Calculated rise time (Typical)[3]	*Full scale range setting*	*TLA7E1 and TLA7E2*	*TLA7D1 and TLA7D2*
Typical full-bandwidth rise times are shown in the chart to the right	10.1 V – 100 V	900 ps	900 ps
	100 mV – 10 V	450 ps	900 ps
	50 mV – 99.5 mV	600 ps	900 ps
	20 mV – 49.8 mV	750 ps	900 ps
	10 mV – 19.9 mV	900 ps	900 ps
Crosstalk (channel isolation)	≥300:1 at 100 MHz and ≥100:1 at the rated bandwidth for the channel's sensitivity (Full Scale Range) setting, for any two channels having equal sensitivity settings		
Digitized bits	8		

Table 77: DSO module signal acquisition system (Cont.)

Characteristic	Description		
Effective bits, real time sampling (Typical)	*Input frequency*	*TLA7E1 and TLA7E2 5 GS/s (each channel)*	*TLA7D1 and TLA7D2 2.5 GS/s (each channel)*
	10.2 MHz	6.2 bits	6.2 bits
	98 MHz	6.1 bits	6.1 bits
	245 MHz	6.0 bits	6.0 bits
	490 MHz	5.7 bits	5.7 bits
	990 MHz	5.2 bits	N/A
Frequency limit, upper, 20 MHz bandwidth limited (Typical)	20 MHz		
Frequency limit, upper, 250 MHz bandwidth limited (Typical)	250 MHz		
Input channels	*Product*		*Channels*
	TLA7E2		Four
	TLA7D2		Four
	TLA7E1		Two
	TLA7D1		Two
Input coupling	DC, AC, or GND[4]		
Input impedance, DC-1 MΩ coupled	1 MΩ ±0.5% in parallel with 10 pF ±3 pF		
Input impedance selections	1 MΩ or 50 Ω		
Input resistance, DC-50 Ω coupled	50 Ω ±1%		
Input VSWR, DC-50 Ω coupled	≤1.3:1 from DC - 500 MHz, ≤1.5:1 from 500 MHz - 1 GHz		
Input voltage, maximum, DC-1 MΩ, AC-1 MΩ, or GND coupled	300 V_{RMS} but no greater than ±420 V peak, Installation category II, derated at 20 dB/decade above 1 MHz		
Input voltage, maximum, DC-50 Ω or AC-50 Ω Coupled	5 V_{RMS}, with peaks ≤ ±25 V		
Lower frequency limit, AC coupled (Typical)	≤10 Hz when AC-1 MΩ Coupled; ≤200 kHz when AC-50 Ω Coupled[5]		
↙ Random noise	*Bandwidth selection*		*RMS noise*
	Full		≤(350 μV + 0.5% of the full scale Setting)
	250 MHz		≤(165 μV + 0.5% of the full scale Setting)
	20 MHz		≤(75 μV + 0.5% of the full scale Setting)

Table 77: DSO module signal acquisition system (Cont.)

Characteristic	Description				
Range, internal offset	*Full scale range setting*	*Offset range*			
	10 mV – 1 V	±1 V			
	1.01 V – 10 V	±10 V			
	10.1 V – 100 V	±100 V			
Range, sensitivity (full scale range), all channels	10 mV to 100 V[6]				
Step response settling errors (Typical)[7, 8]	*Full scale range setting*	*± Step response*	*Maximum settling error (%) at*		
			20 ns	*100 ns*	*20 ms*
	10 mV – 1 V	≤2 V	0.5%	0.2%	0.1%
	1.01 V – 10 V	≤20 V	1.0%	0.5%	0.2%
	10.1 V – 100 V	≤200 V	1.0%	0.5%	0.2%

[1]   **Net offset is the nominal voltage level at the digitizing oscilloscope input that corresponds to the center of the A/D Converter dynamic range. Offset accuracy is the accuracy of this voltage level.**

[2]   **The limits given are for the ambient temperature range of 0 °C to +30 °C. Reduce the upper bandwidth frequencies by 5 MHz for each °C above +30 °C. The bandwidth must be set to FULL.**

[3]   **Rise time (rounded to the nearest 50 ps) is calculated from the bandwidth when Full Bandwidth is selected. It is defined by the following formula:**

   Rise Time (ns) = 450 ÷ BW (MHz)

[4]   **GND input coupling disconnects the input connector from the attenuator and connects a ground reference to the input of the attenuator.**

[5]   **The AC Coupled Lower Frequency Limits are reduced by a factor of 10 when 10X passive probes are used.**

[6]   **The sensitivity ranges from 10 mV to 100 V full scale in a 1- 2- 5 sequence of coarse settings. Between coarse settings, you can adjust the sensitivity with a resolution equal to 1% of the more sensitive coarse setting. For example, between the 500 mV and 1 V ranges, the sensitivity can be set with 5 mV resolution.**

[7]   **The Full Bandwidth settling errors are typically less than the percentages from the table.**

[8]   **The maximum absolute difference between the value at the end of a specified time interval after the mid-level crossing of the step, and the value one second after the mid-level crossing of the step, expressed as a percentage of the step amplitude. See IEEE std. 1057, Section 4.8.1, *Settling Time Parameters*.**

Table 78: DSO module timebase system

Characteristic	Description	
Range, Extended Realtime Sampling Rate	5 S/s to 10 MS/s in a 1–2.5–5 sequence	
Range, Realtime Sampling Rate	*Products*	*Limits*
	TLA7E1 and TLA7E2	25 MS/s to 5 GS/s on all channels simultaneously in a 1–2.5–5 sequence
	TLA7D1 and TLA7D2	25 MS/s to 2.5 GS/s on all channels simultaneously in a 1–2.5–5 sequence
Record Length	512, 1024, 2048, 4096, 8192, and 15000	
⤳ Long Term Sample Rate	±100 ppm over any ≥ 1 ms interval	

Table 79: DSO module trigger system

Characteristic	Description	
⤳ Accuracy (Time) for Pulse Glitch or Pulse Width Triggering	*Time Range*	*Accuracy*
	2 ns to 500 ns	±(20% of Setting + 0.5 ns)
	520 ns to 1 s	±(104.5 ns + 0.01% of Setting)
⤳ Accuracy (DC) for Edge Trigger Level, DC Coupled	±((2% × | Setting) |) + 0.03 of Full Scale Range + Offset Accuracy) for signals having rise and fall times ≥20 ns	
Range (Time) for Pulse Glitch and Pulse Width Triggering	2 ns to 1 s	
Range, Trigger Level	*Source*	*Range*
	Any Channel	±100% of full scale range
Range, Trigger Point Position	Minimum: 0% Maximum: 100%	
Resolution, Trigger Level	0.2% of full scale for any Channel source	
Resolution, Trigger Position	One Sample Interval at any Sample Rate	
Sensitivities, Pulse-Type Runt Trigger *(Typical)*	10% of full scale, from DC to 500 MHz, for vertical settings >100 mV full scale and ≤10 V full scale at the BNC input	
Sensitivities, Pulse-Type Trigger Width and Glitch *(Typical)*	10% of full scale for vertical settings >100 mV full scale and ≤10 V full scale at the BNC input	

Table 79: DSO module trigger system (Cont.)

Characteristic	Description		
✔ Sensitivity, Edge-Type Trigger, DC Coupled	The minimum signal levels required for stable edge triggering of an acquisition when the trigger source is DC-coupled		
	Products	*Trigger Source*	*Sensitivity*
	TLA7E1 and TLA7E2	Any Channel	3.5% of Full Scale Range from DC to 50 MHz, increasing to 10% of Full Scale Range at 1 GHz
	TLA7D1 and TLA7D2	Any Channel	3.5% of Full Scale Range from DC to 50 MHz, increasing to 10% of Full Scale Range at 500 MHz
Sensitivity, Edge-Type Trigger, Not DC Coupled (Typical)	*Trigger Coupling*	*Typical Signal Level for Stable Triggering*	
	AC	Same as the DC-coupled limits for frequencies above 60 Hz; attenuates signals below 60 Hz	
	High Frequency Reject	One and one-half times the DC-coupled limits from DC to 30 kHz; attenuates signals above 30 kHz	
	Low Frequency Reject	One and one-half times the DC-coupled limits for frequencies above 80 kHz; attenuates signals below 80 kHz	
	Noise Reject	Three times the DC-coupled limits	
Time, Minimum Pulse or Rearm, and Minimum Transition Time, for Pulse-Type Triggering (Typical)	For vertical settings >100 mV and ≤10 V at the BNC input		
	Pulse Class	*Minimum Pulse Width*	*Minimum Rearm Width*
	Glitch	1 ns	2 ns + 5% of Glitch Width Setting
	Width	1 ns	2 ns + 5% of Width Upper Limit Setting
Trigger Position Error, Edge Triggering (Typical)	*Acquisition Mode*	*Trigger Position Error[1]*	
	Sample	±(1 Sample Interval + 1 ns)	

[1] **The trigger position errors are typically less than the values given here. These values are for triggering signals having a slew rate at the trigger point of ≥5% of full scale/ns.**

Table 80: DSO module front-panel connectors

Characteristic	Description
✔ Probe Compensator, Output Voltage The Probe Compensator output voltage in peak-to-peak Volts	0.5 V (base–top) ± 1% into a ≥ 50 Ω load

Table 81: DSO module mechanical

Characteristic	Description	
Slot width	Requires 2 mainframe slots	
Weight (Typical)	*Products*	*Weight*
	TLA7D1 and TLA7E1	2.44 kg (5.38 lbs)
	TLA7D2 and TLA7E2	2.55 kg (5.63 lbs)
Shipping Weight (Typical)	*Products*	*Weight*
	TLA7D1 and TLA7E1	6.35 kg (14 lbs)
	TLA7D2 and TLA7E2	7.71 kg (17 lbs)
Overall Dimensions	Height: 262.05 mm (10.32 in) Width: 60.66 mm (2.39 in) Depth: 373.38 mm (14.70 in)	

External Oscilloscope (iView) Characteristics

Table 82 lists the characteristics for iView (Integrated View) and for the Tektronix logic analyzer when connected to an external oscilloscope. For detailed information on the individual specifications of the external oscilloscope, refer to the documentation that accompanies the oscilloscope.

Table 82: External oscilloscope (Integrated View or iView) characteristics

Characteristic	Description
Supported Tektronix logic analyzer instruments	TLA600 series, TLA5000 series TLA714, TLA715 TLA720, TLA721
TLA application software version	V4.2 or greater
Minimum recommended TLA controller DRAM[1]	256 MB
Supported external oscilloscopes as of February, 2004 *(for the latest list of supported external oscilloscopes, visit our website at www.tektronix.com/la)*	TDS1000 Series[2] TDS2000 Series[2] TDS3000/3000B Series (TDS3GM GPIB/RS232 communication module required) TDS5000/TDS5000B Series TDS6000/TDS6000B Series TDS7000/7000B Series CSA7000/7000B Series TDS654C, TDS684C, TDS694C TDS724C, TDS754C, TDS784C, TDS724D, TDS754D, TDS784D, TDS794D
External oscilloscope software or firmware version number	
TDS684C, TDS694C	Any version
TDS3000 series	Any version
TDS5000 series	Any version
TDS6000 series	Any version
TDS7000, CSA7000 series	Version 1.2 or greater
Maximum number of external oscilloscopes	One per Tektronix logic analyzer
iView cable length	6.56 ft (2 m)
Time correlation uncertainty[3] (*Typical at system trigger*)	
3 ns	Logic analyzer triggers external oscilloscope (2 ns + logic analyzer sample period + external oscilloscope sample period)

Table 82: External oscilloscope (Integrated View or iView) characteristics (Cont.)

Characteristic	Description
5 ns	External oscilloscope triggers logic analyzer (4 ns + logic analyzer sample period + external oscilloscope sample period)

[1]   **If DRAM is less than 256 MB, the record length of the external oscilloscope may be limited to 1 M.**

[2]   **The first time that you take an acquisition after changing the horizontal scale setting on TDS1000 or TDS2000 series oscilloscopes, the TLA and TDS waveform edges may not be aligned within the listed specification. You can realign the waveform positions in the waveform window that contains the TDS1000/2000 data (Menu bar > Data > Time Alignment). Make sure that the external oscilloscope is the data source and then adjust the time offset to align the waveforms. Use the following approximate offsets for various horizontal scale settings:**

Horizontal scale	Time offset	Horizontal scale	Time offset	Horizontal scale	Time offset
10 ns	-365 ns	25 ns	-325 ns	50 ns	-217 ns
100 ns	-5 ns	250 ns	-11 ns	500 ns	-18 ns
1 µs	-12 ns	2.5 µs	-50 ns	5 µs	-120 ns
10 µs	-250 ns	25 µs	-650 ns	50 µs	-1300 ns
100 µs	-2600 ns	250 µs	+500 ns	500 µs	+1000 ns

[3]   **Includes sampling uncertainty, typical jitter, slot-to-slot skew, and probe-to-probe variations to provide a *typical* number for the measurement.**